

Supporting information

Effect of yttrium, ytterbium with tungsten co-doping on light absorption and charge transport properties of bismuth vanadate photoanodes to achieve superior photoelectrochemical water splitting

Umesh Prasad^{1*}, Jyoti Prakash¹ and Arunachala M. Kannan^{1*}

¹ The Polytechnic School, Ira A. Fulton Schools of Engineering, Arizona State University, Mesa, AZ 85212, USA

*Corresponding Author: amk@asu.edu (AM Kannan)/ uprasad1@asu.edu (Umesh Prasad)

PEC measurement, potential conversion, Impedance measurement, electrochemical surface area and Space width charge region calculation

The exposed backside area of photoanode for light illumination was 1 cm². For 1 sun illumination, a solar simulator (Newport 67005) equipped with an AM 1.5G filter used as a light source which is integrated with potentiostat/galvanostatic (PARSTAT-2273). The photoanodes were mounted perpendicular to the light source to maintain measurement accuracy. 1 sun illumination intensity was assured in Figure S1a which shows solar light intensity calibration with the X-Y direction at 7 cm from the light source.

The light intensity distribution for the solar simulator (Newport Model # 67005) was determined using a lux meter (Silicon photo-detector; Extech Model # SDL400) using insulating tape as a black mask with hole of 1 cm x 0.8 cm (size of exposed thin film) and calibrated with the X-Y direction at 7 cm from the light source. It was validated from the Figure S1a that the light illumination is 100 mW.cm⁻² irradiating on the photoanode surface (geometrical area = 1 cm²) after placing the sample at the center. Slight error in sample placement will affect (reduce) the light illumination intensity on the photoanode surface. An assumed experimental error in the placement of photoanodes are in the order of 0.25 cm which provides a representative value to the alignment of the photoanode with the naked eye. This led to the light illumination intensity variation in the range of 95-100 mW.cm⁻² which is small enough to avoid. The PEC measurement was conducted in the open environment inside the lab. The other errors such as reflection from glass-air media, glass-water interfaces and the electrolyte solution media during measurements would cause further decrease in the actual light illumination intensity below 1 sun. For clarity, we have placed the sample approximately 2 cm from the edge of the glass. It is worth noting that we followed the protocol in the literature¹.

The potential was converted to reverse hydrogen electrode (RHE) as given relationship (eq 1).

$$E_{RHE} = E_{SCE}^0 + E_{SCE} + 0.059 pH \quad (1)$$

Where $E_{SCE}^0 = 0.2415 V$ vs. RHE, at 298 K

Electrochemical Impedance measurement was carried out in frequency range 100 mHz to 100 kHz with AC amplitude of 20 mV at 1.23 V vs RHE under 1 sun illumination and using 0.1 M K₂HPO₄ electrolyte (pH 8.0). Resistance and capacitance values were estimated by curve fitting using Randles circuits in software EC-Lab v11.20 . Electrochemical surface area (ECSA) was estimated by analyzing current voltammetry (CV) in the dark (non-faradaic zone) at various scan rate as given in literature². Flat band (onset) potential was measured by Mott–Schottky at 1 kHz in dark with AC amplitude of 20 mV at 1.23 V vs RHE in 0.1 M K₂HPO₄ electrolyte (pH 8.0) by relationship given in eq (2)³.

$$\frac{1}{C^2} = \frac{2}{(\epsilon\epsilon_0 A^2 e N_D)} (V_{app} - V_{FB} - \frac{K_B T}{e}) \quad (2)$$

Where, C is capacitance in space charge region; ϵ is relative permeability which is taken 68 for the calculation; ϵ_0 is vacuum permeability ($8.8 \times 10^{-12} F m^{-1}$); A (cm²) is area of photoanode thin film; e is charge of electron ($1.602 \times 10^{-19} C$); N_D is number of charge carrier per cm⁻³ and estimated from Mott-Schottky measurement plot (Table S3); V_{app} (vs RHE) applied potential; V_{FB} flat band potential estimated from Mott-Schottky plot; K_B Boltzmann constant ($1.38 \times 10^{-23} JK^{-1}$); T (K) is the temperature at which measurement performed (298K). Width space charge region (W_{SCL}) or depletion layer was estimated from eq (3)³.

$$W_{SCL} = \sqrt{\frac{2\epsilon\epsilon_0}{(A^2 e N_D)} \left(V_{app} - V_{FB} - \frac{K_B T}{e} \right)} \quad (3)$$

Theoretical photocurrent calculation:

Calculate light harvesting efficiency (LHE) which is also known as absorption efficiency ϕ_{abs} from the absorption by given relationship (eq 4)

$$LHE = 1 - 10^{-A(\lambda)} = \phi_{abs} \quad (4)$$

A: absorbance with wavelength (λ)

In the next step photon energy and photon flux calculated from AM1.5G solar irradiance with wavelength by following relation (eq 3-5).

$$E(\lambda) = h \times C / \lambda \quad (5)$$

$E(\lambda)$: photon energy h : Planck constant C : speed of the light

$$\text{Number of photons} = h \times C / \lambda \quad (6)$$

$$\text{Photons flux } (\phi(\lambda)) = P(\lambda) / E(\lambda) \quad (7)$$

Finally, theoretical photocurrent calculated assuming 100% incident to photon conversion efficiency (IPCE) and by following relationship^{4,5}.

$$J_{theoretical} = \int_{\lambda_1}^{\lambda_2} e \times \phi(\lambda) \times LHE \times d\lambda \quad (8)$$

Charge separation and charge transfer efficiency calculation:

Theoretical photocurrent undergoes two major losses bulk and surface recombination which are known as charge separation (ϕ_{sep}) and charge transfer or charge injection efficiency (ϕ_{trans}), given relationship eq (9).

$$J_{H_2O} = J_{theoretical} \times \phi_{sep} \times \phi_{trans} \quad (9)$$

The transfer efficiency is almost 100% in the presence of hole scavengers, which is given by relationship eq (10)⁵.

$$J_{Na_2SO_3} = J_{theoretical} \times \phi_{trans} \quad (10)$$

Now, ϕ_{sep} and ϕ_{trans} can be calculated using eq (8-10)

Charge IPCE and APCE calculation:

PCD (J_{mono}) was measured at different wavelength using light monochromator (Newport CS-130) and PARSTAT-2273 galvanostat/potentiostat in 0.1 M K_2HPO_4 electrolyte (pH 8.0). Light intensity (P_{mono}) coming out of monochromator was measure using power meter (Newport PMKIT-05-01). IPEC was measured by relationship given in eq (11).

$$IPCE = \frac{\text{Number of electrons}}{\text{Number of photons}} = \frac{J_{mono} \times h \times C}{P_{mono} \times \lambda} \quad (11)$$

APCE (absorbed photon-to-current conversion efficiency) is calculated as given relationship in eq (12)

$$APCE = \frac{IPCE}{LHE} \quad (12)$$

Integrated current calculation:

Integrated current ($J_{\text{integrated}}$) calculated using eq (4-7) and relationship given in eq (13)

$$J_{\text{Integrated}} = \int_{\lambda_1}^{\lambda_2} e \times \phi(\lambda) \times IPCE \times LHE \times d\lambda \quad (13)$$

Band bending calculation:

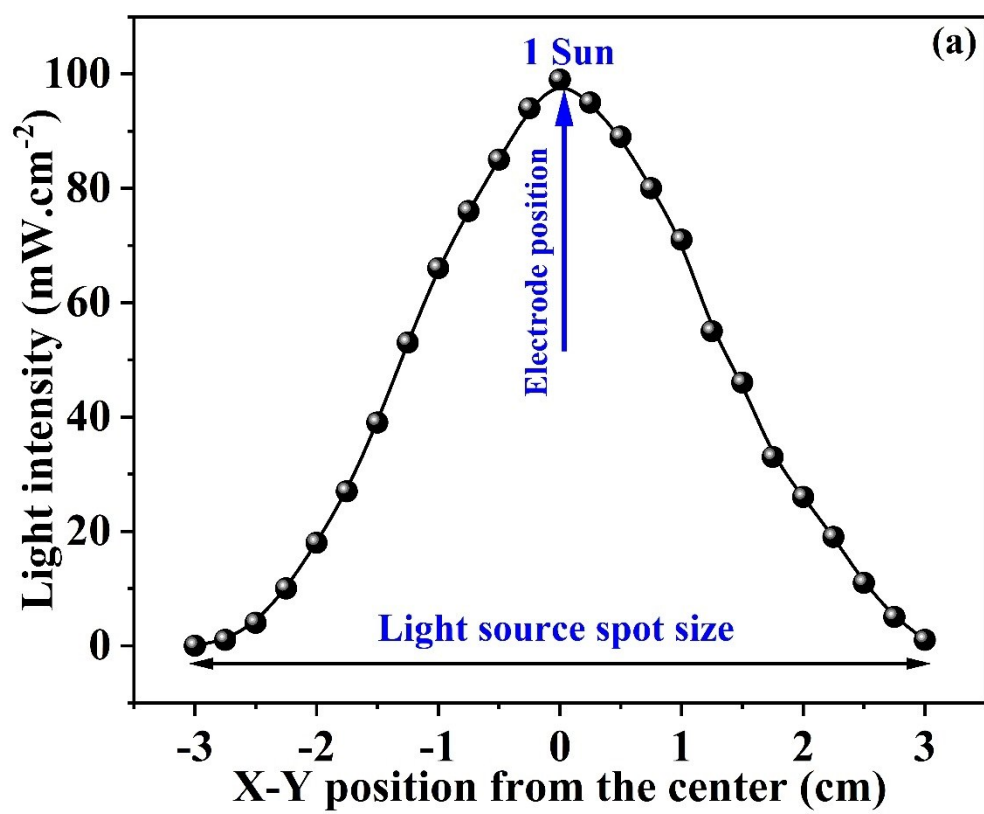
Total amount of band bending at WO₃ and BiVO₄ interface is calculated based on the eq (14)⁶.

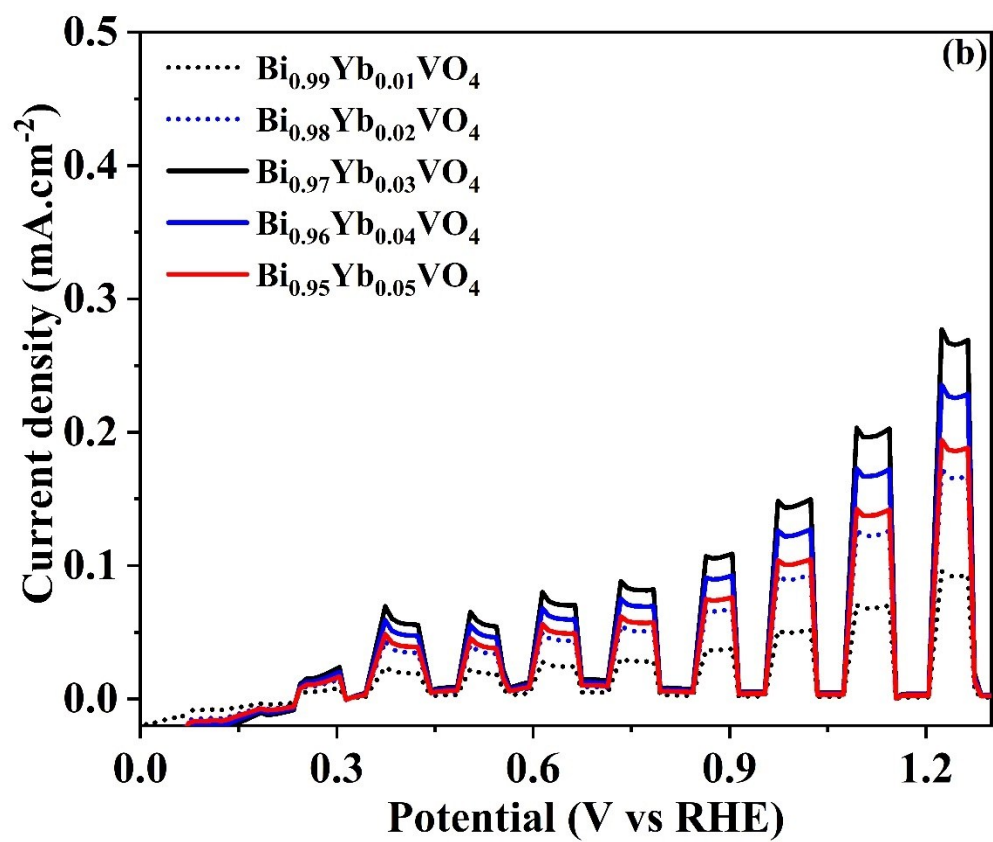
$$\Delta E = E_{F,WO_3} - E_{F,(Y,W):BiVO_4} = k_B T \ln \left(\frac{N_{D,(Y,W):BiVO_4}}{N_{D,WO_3}} \right)$$

Where, E_{F,WO_3} and $E_{F,(Y,W):BiVO_4}$ are the Fermi energy levels of WO₃ and (Y,W):BiVO₄ film respectively.

k_B is Boltzmann constant, T is the temperature and N_{D,WO_3} & $N_{D,(Y,W):BiVO_4}$ are the charge carrier

densities for WO₃ and (Y,W):BiVO₄ film respectively.





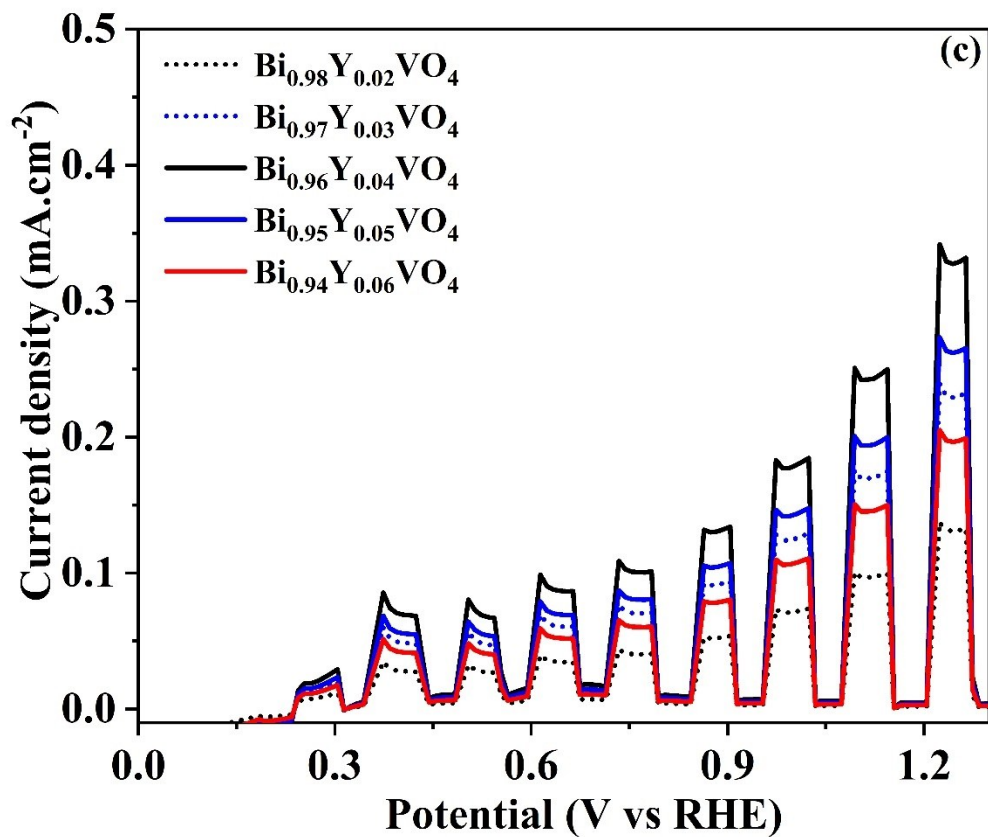
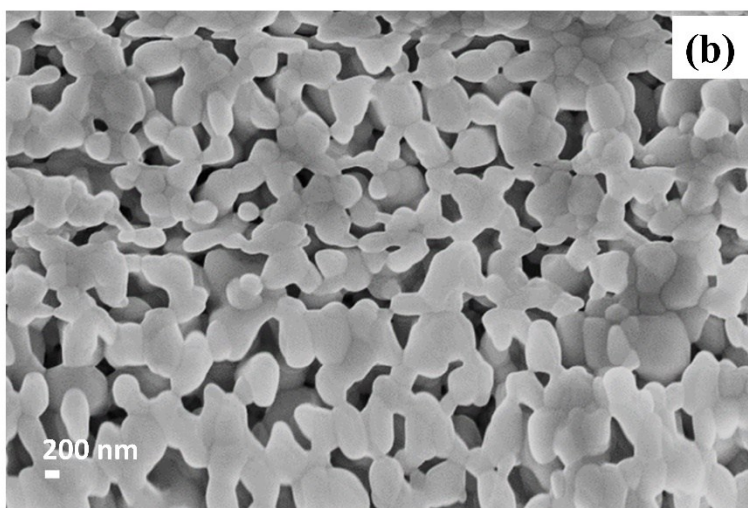
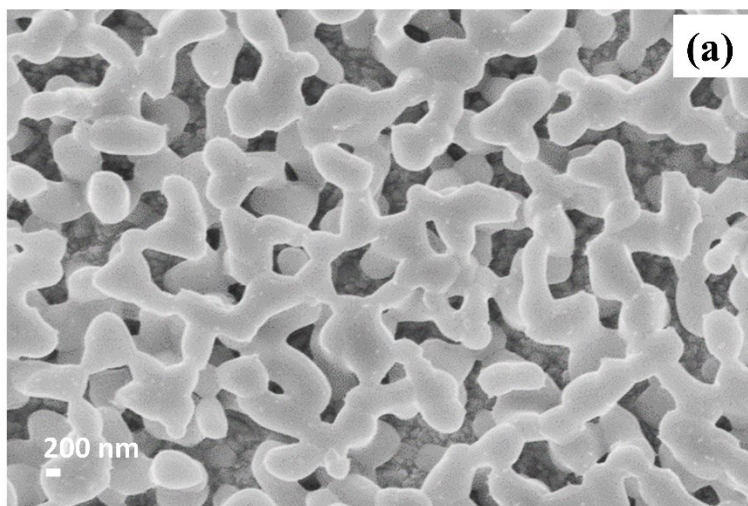
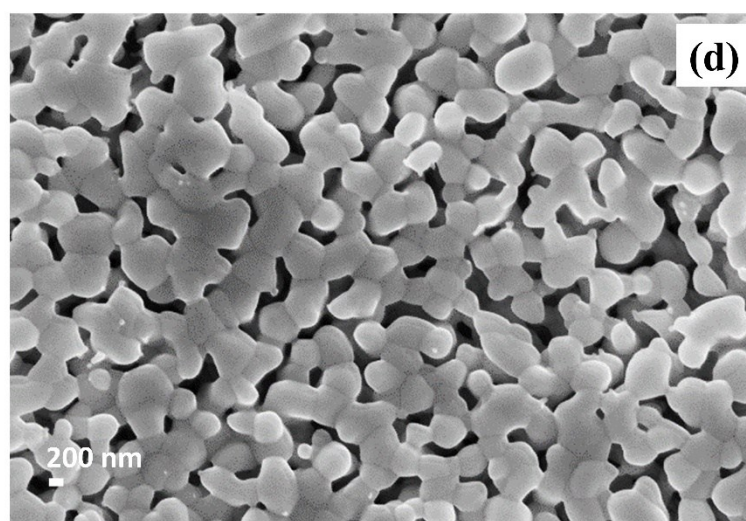
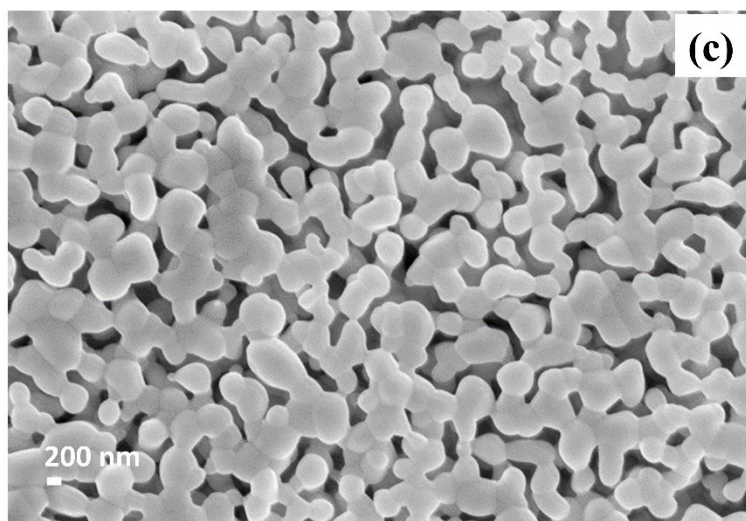
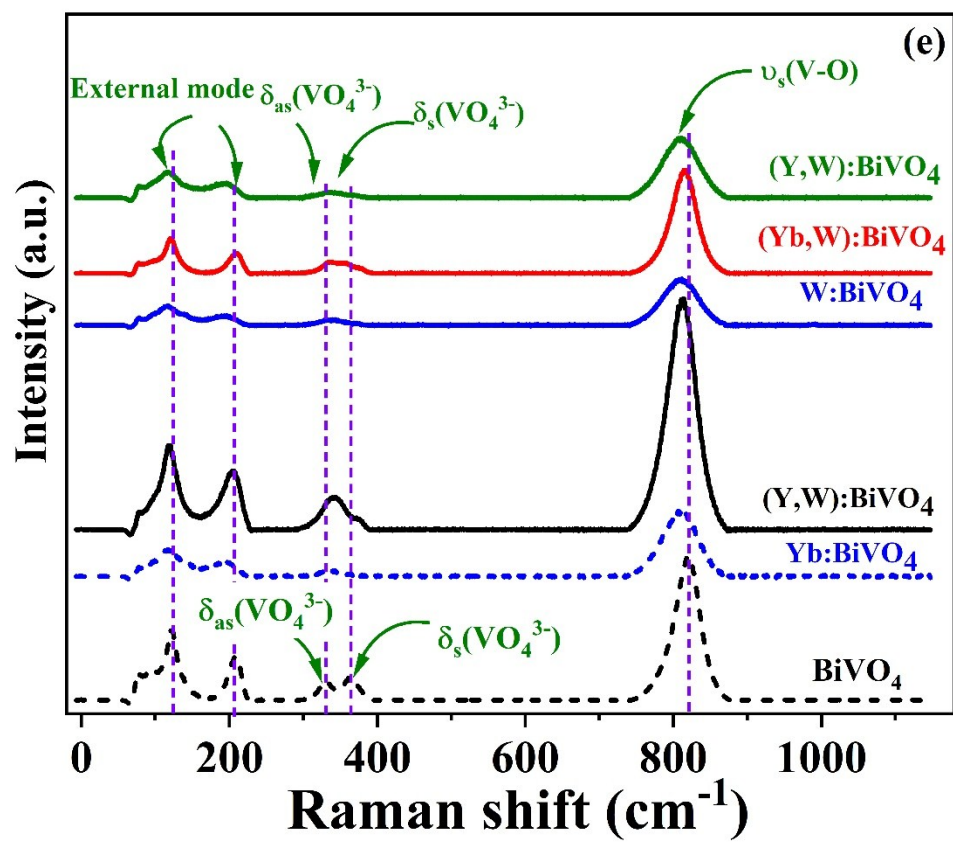
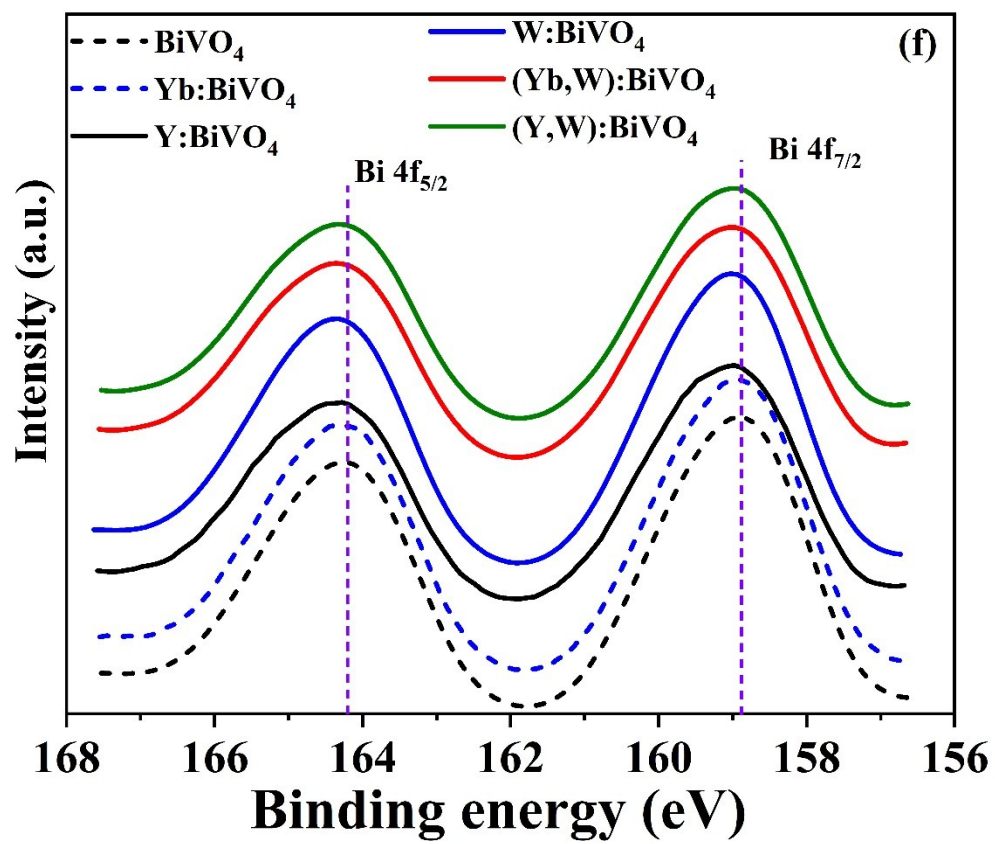


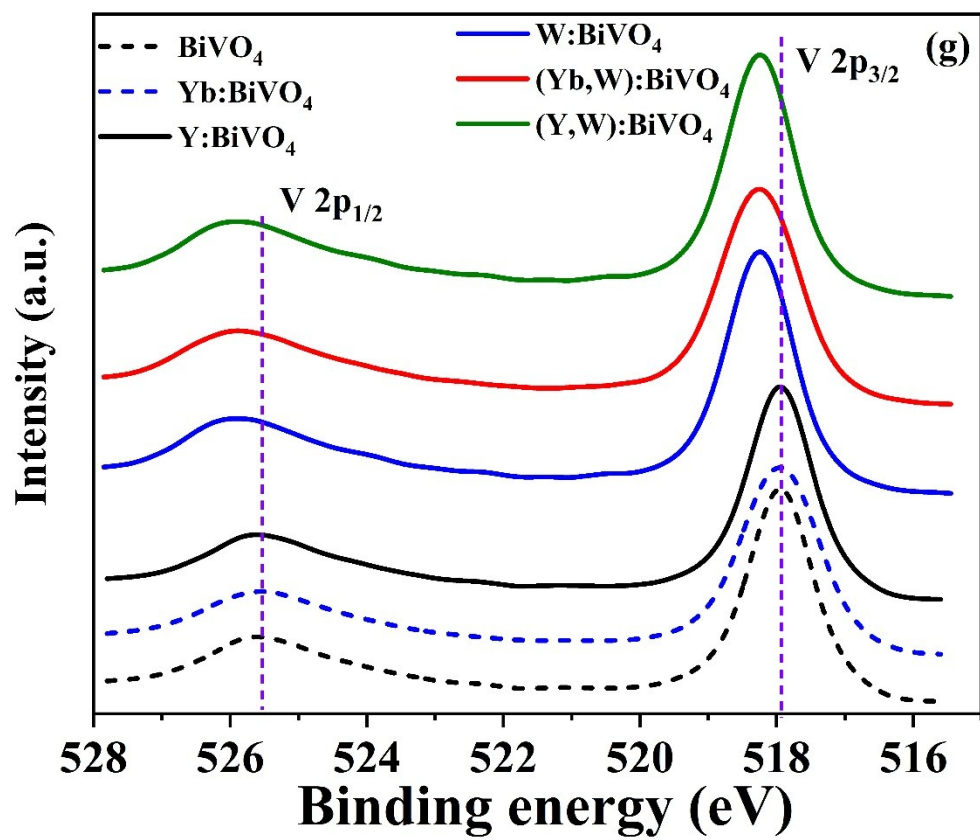
Figure S1 (a) Solar light intensity calibration chart with the X-Y direction at 7 cm from the light source. Linear sweep voltammetry (LSV) curves for (b) Yb (1 – 5%), (c) Y (2 – 6%) doped BiVO_4 .

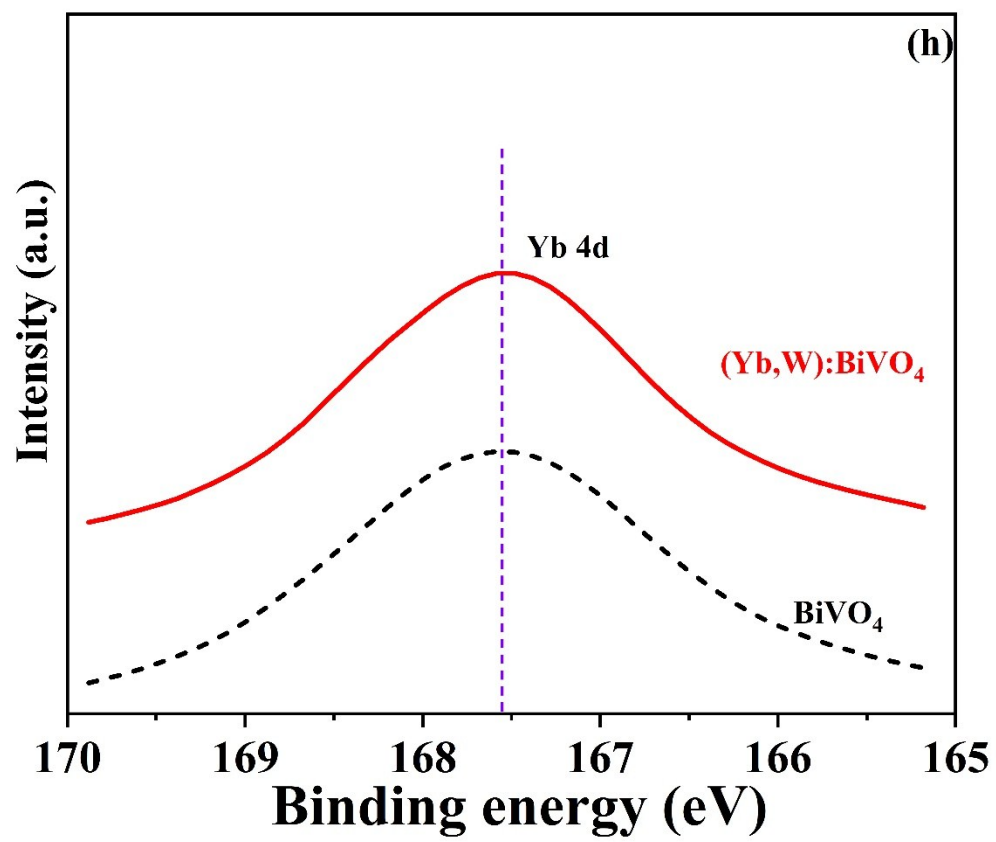


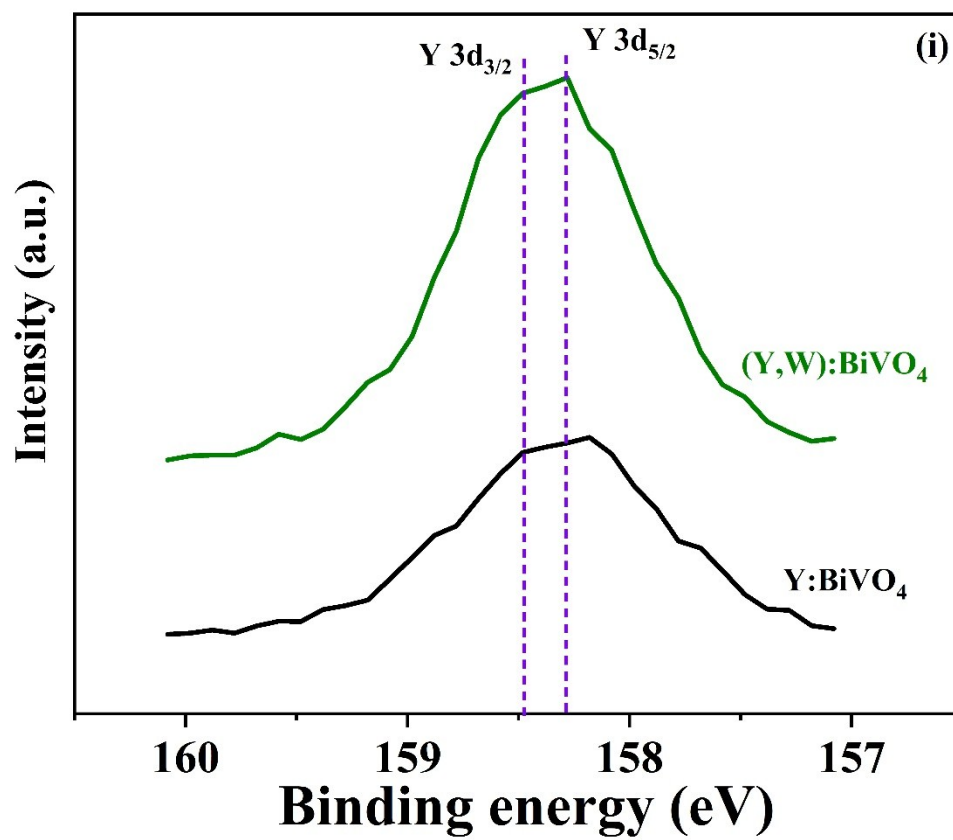












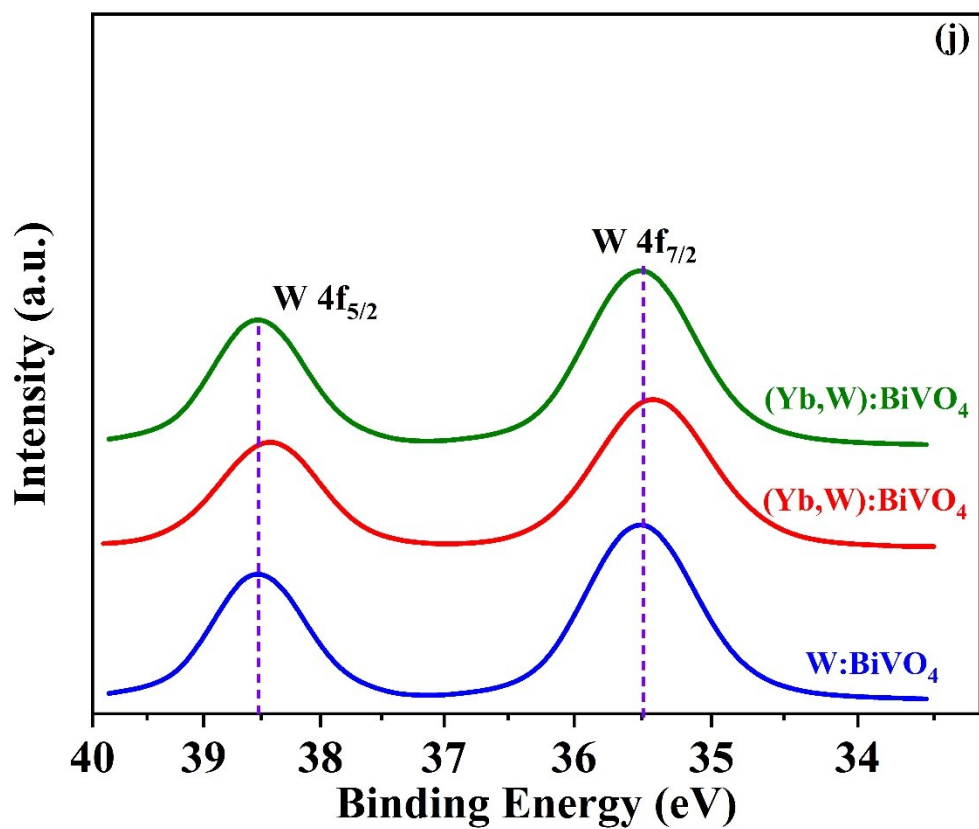
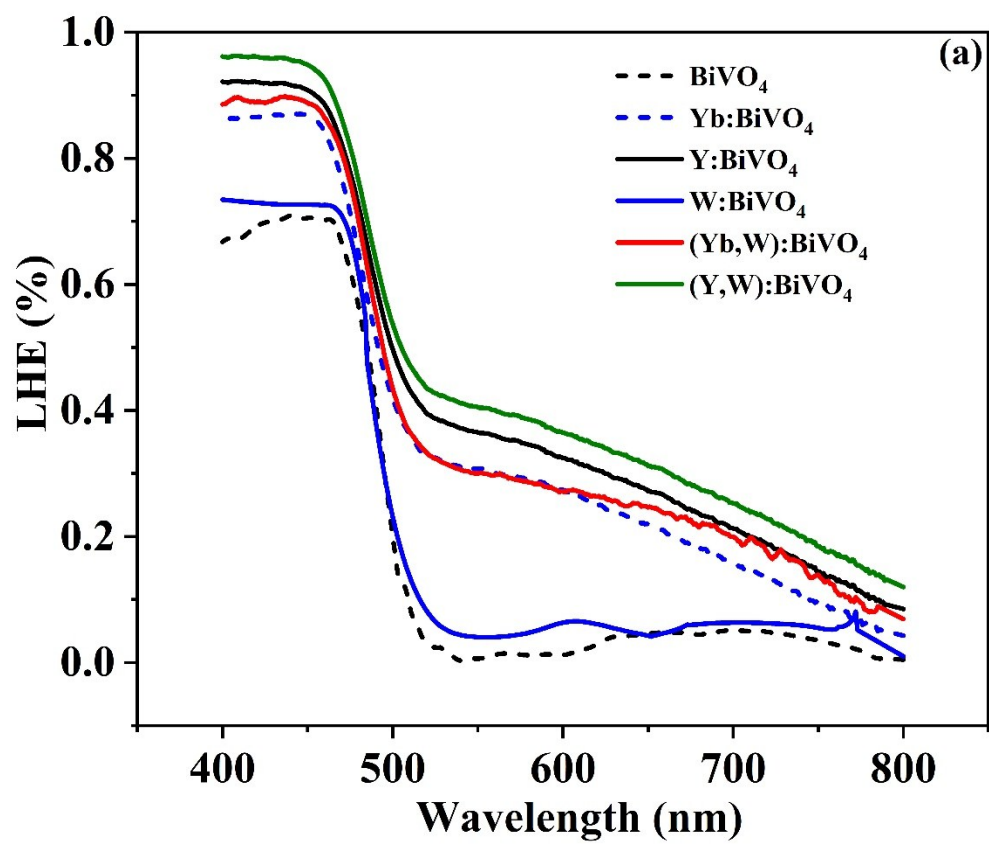
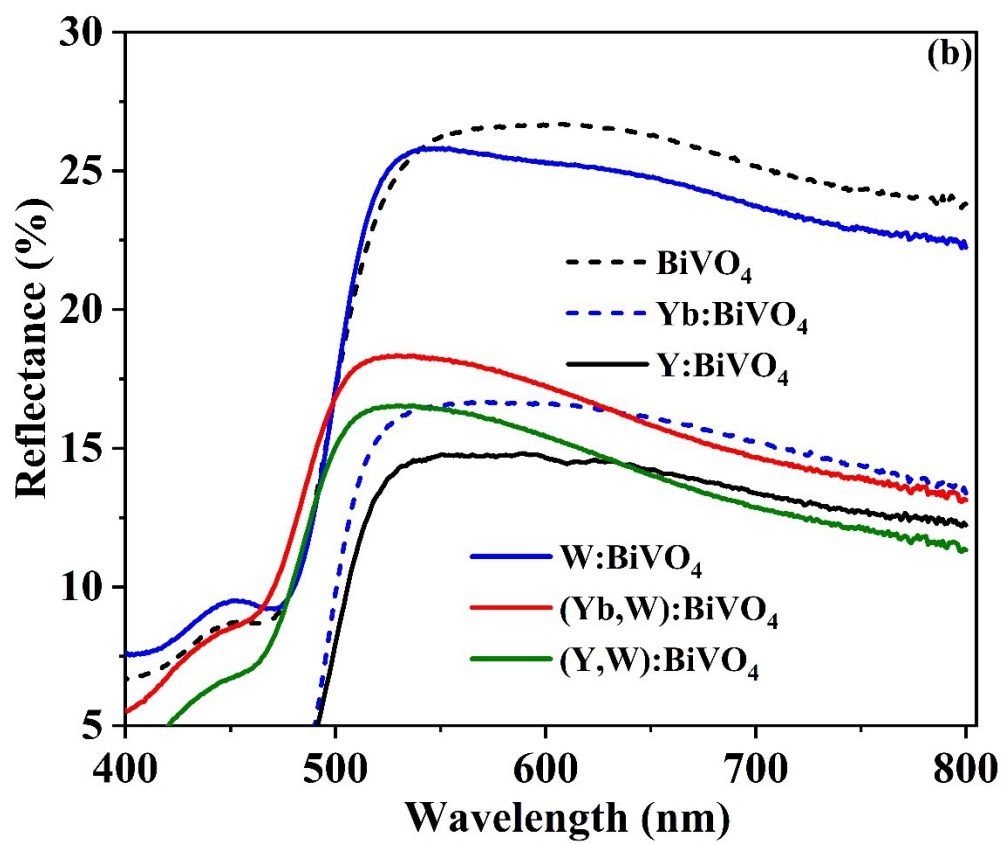
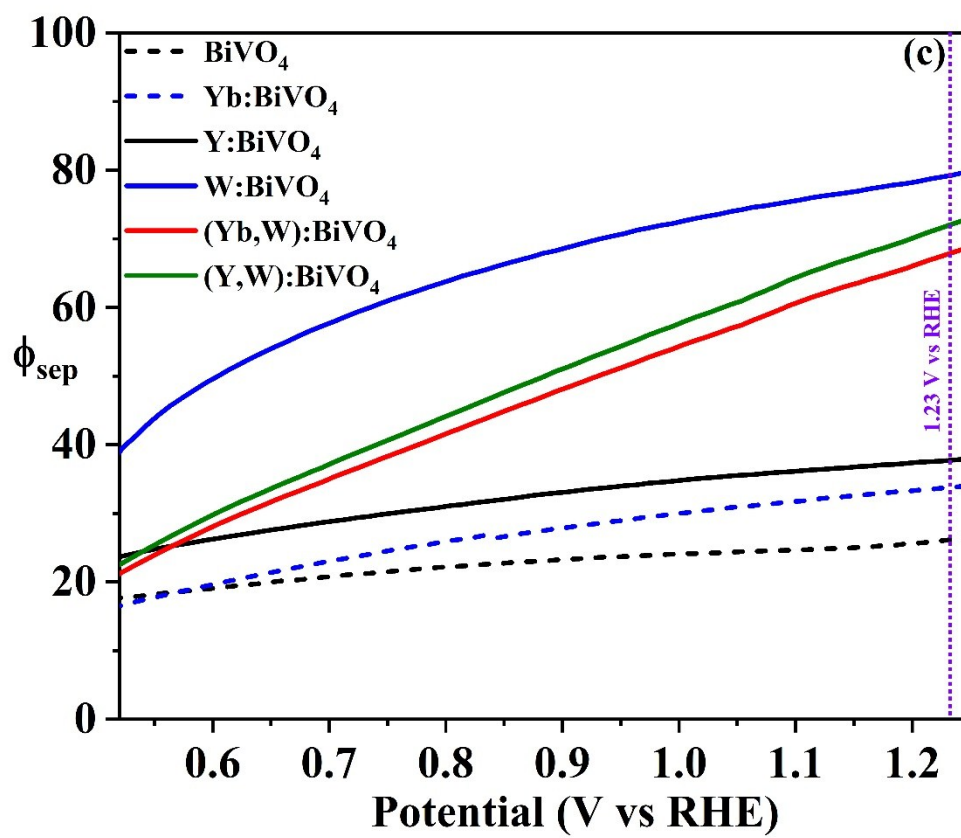
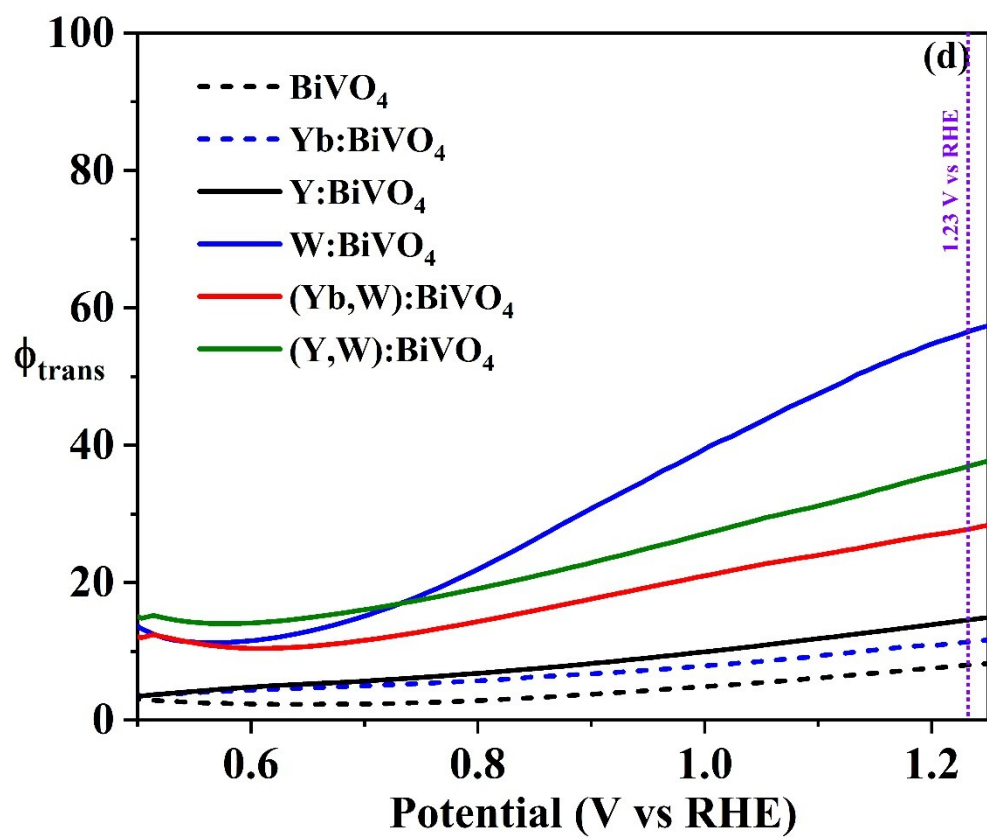


Figure S2 SEM images of (a) BiVO₄ (b) Yb:BiVO₄ (c) Y:BiVO₄ (d) W:BiVO₄. (e) Raman spectra of pristine BiVO₄, Yb:BiVO₄, Y:BiVO₄, W:BiVO₄, (Yb,W): BiVO₄ and (Y,W):BiVO₄ photoanodes. XPS spectra of (f) Bi 4f, (g) V 2p, (h) Yb 4d, (i) Y 3d and (j) W 4f.









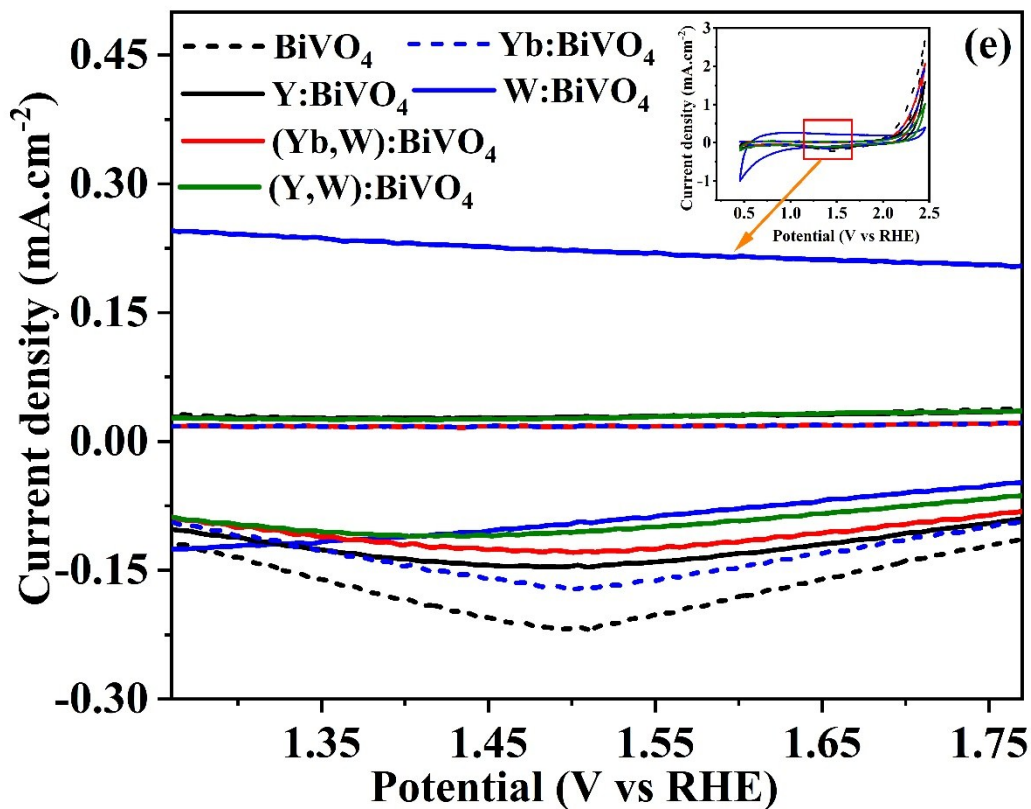
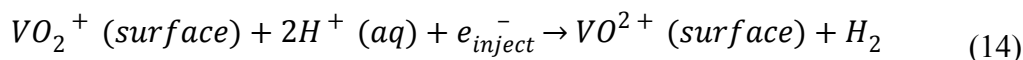
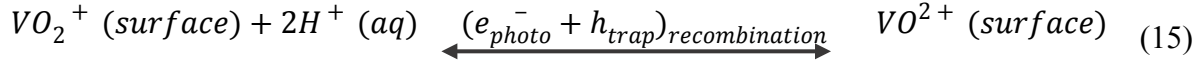


Figure S3 (a) Calculated LHE plot, (b) reflection plot, (c) ϕ_{sep} plot, (d) ϕ_{trans} plot of pristine BiVO_4 , $\text{Yb}:\text{BiVO}_4$, $\text{Y}:\text{BiVO}_4$, $\text{W}:\text{BiVO}_4$, $(\text{Yb,W}):\text{BiVO}_4$ and $(\text{Y,W}):\text{BiVO}_4$ photoanodes. (e) Cyclic voltammetry in dark at 20 mV/sec in 0.1 M K_2HPO_4 .

In order to understand the recombination center or reaction sites at the photoanode surface and electrolyte interface, CV measurement performed in K_2HPO_4 electrolyte from potential 0.45 to 2.5 V vs RHE in the dark (Figure S3e). The observed cathodic peak at ~ 1.45 V vs RHE describes the surface reaction given in eq 14⁷.



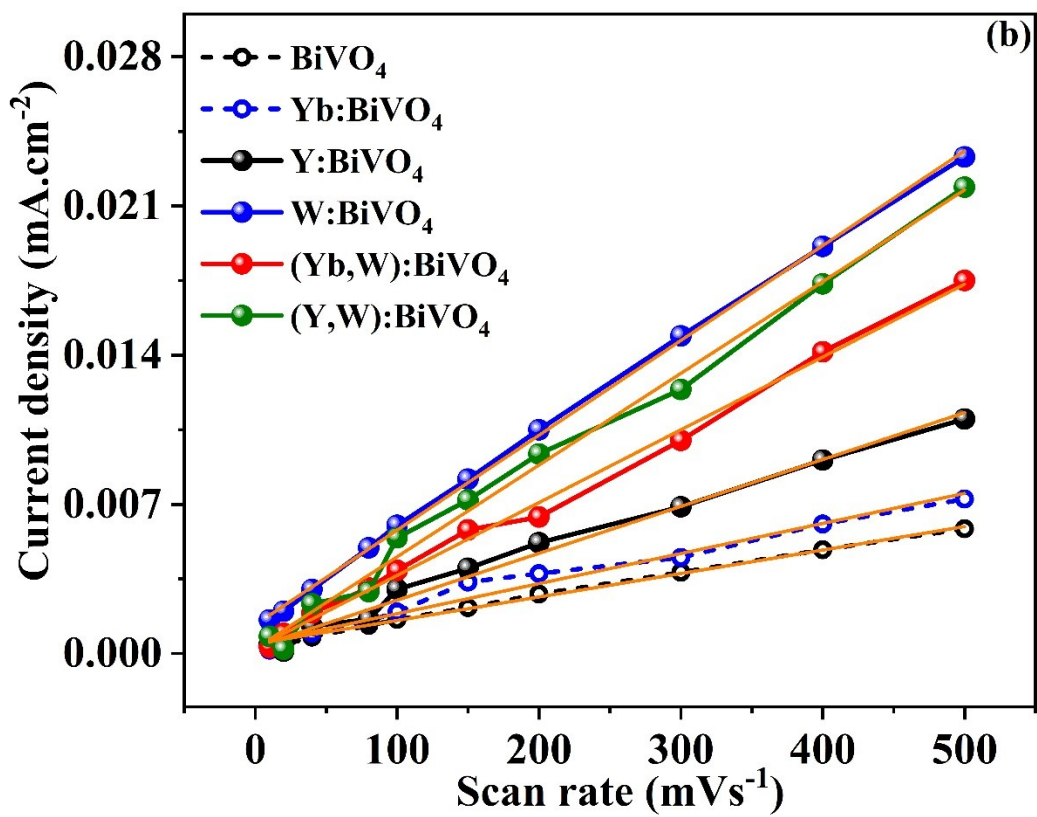
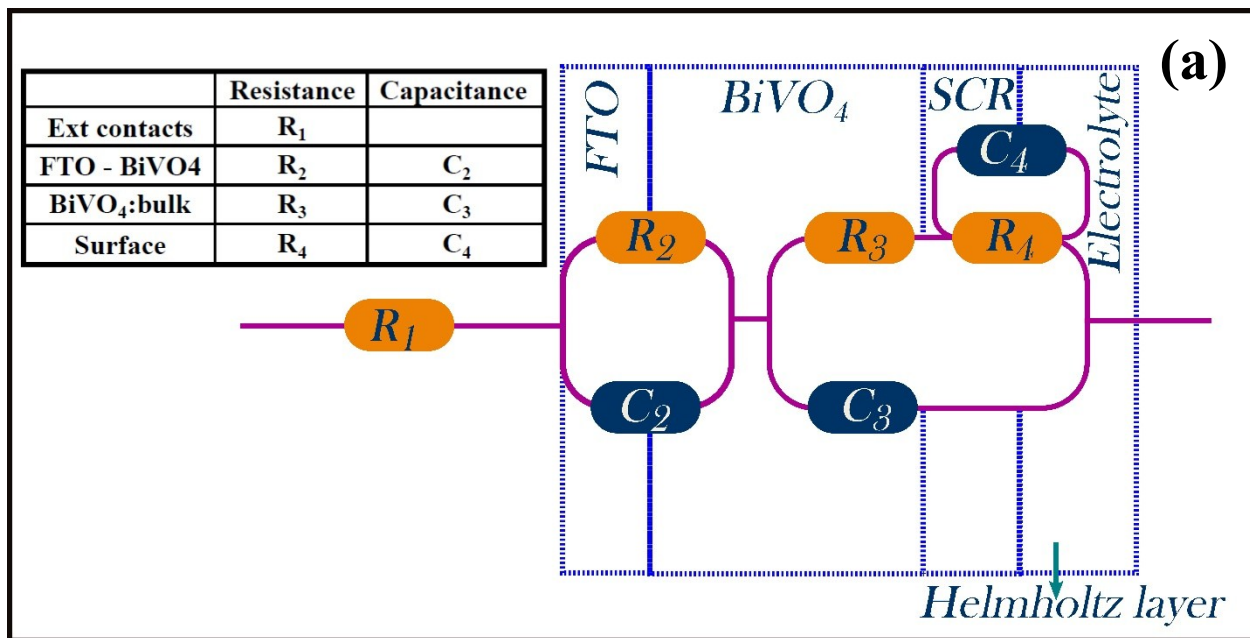
Surface reaction VO_2^+/VO^{2+} is irreversible direct that charge transfer from trap sites (termed as surface state) and detrapping process is slow which lead to accumulation of charges in the trap sites and then increases recombination (eq 15)⁵.

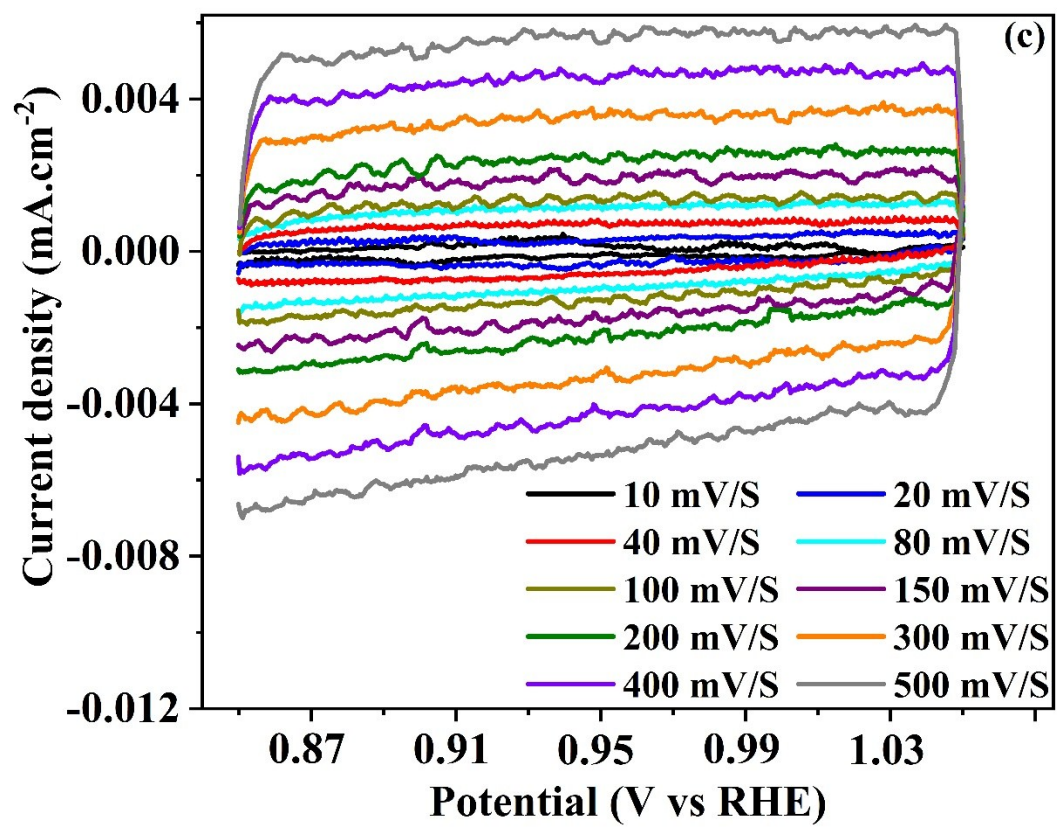


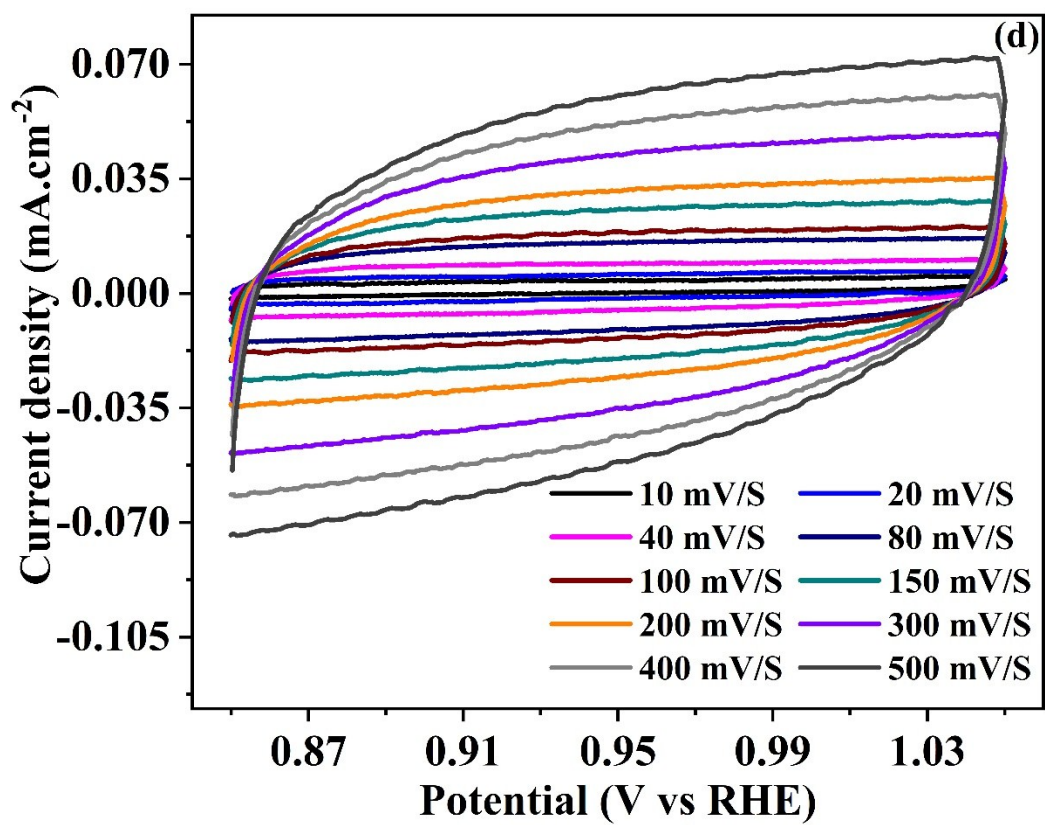
Since the peak potential is greater than the water oxidation potential (1.23 V vs RHE), the potential range for this state extend over the water oxidation in dark. W:BiVO₄ photoanodes shows smaller peak intensity compared to other photoanodes which depicts the low number of trap sites formation which lead to higher PEC performance. The peak intensity (estimated by peak ~1.45 V vs RHE fitting using Matlab software) decreasing sequence is as follows: W:BiVO₄ > (Y,W):BiVO₄ > (Yb,W):BiVO₄ > Y:BiVO₄ > Yb:BiVO₄ > BiVO₄.

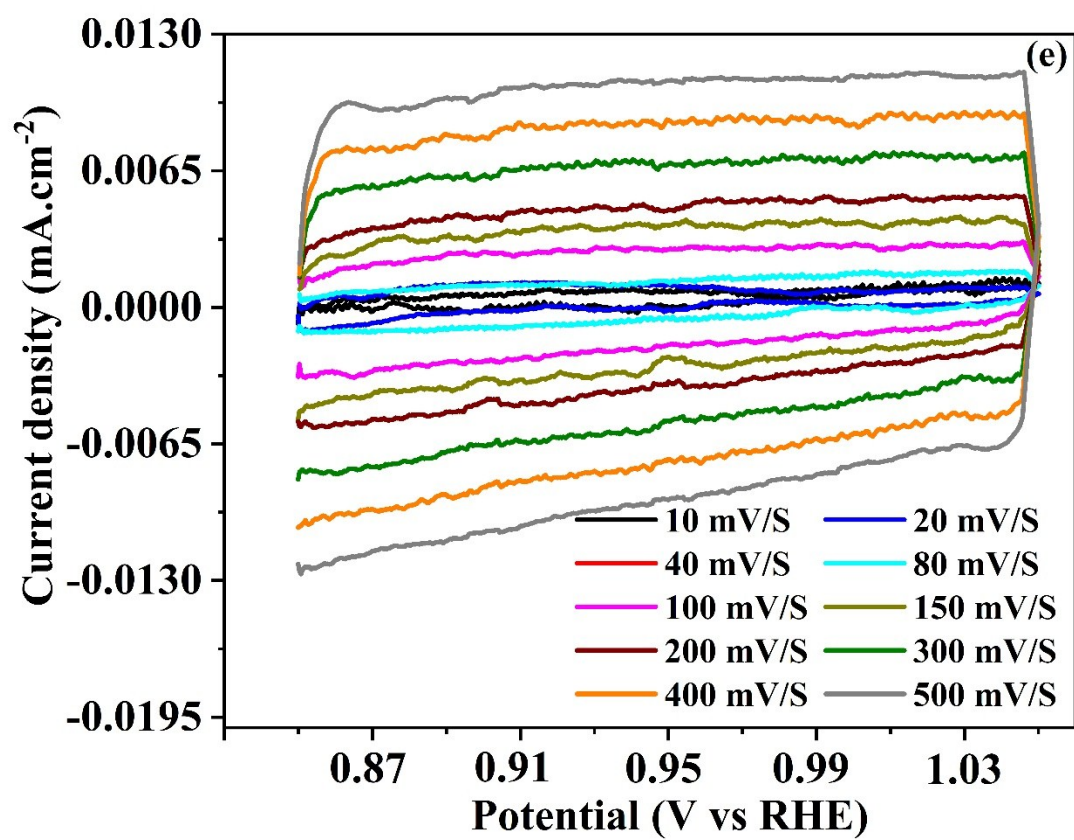
The formation of heterojunction and surface OER catalyst over photoanodes revealed that the WO₃/(Y,W):BiVO₄/Fe:NiO/Co-Pi photoanode shows the best performance rather than WO₃/W:BiVO₄/Fe:NiO/Co-Pi. The observed phenomena is explained by the formation of recombination centers on the electrode surface (surface states) with Y/Yb doping along with W⁷. The SS has been reported to influence charge transfer at the semiconductor electrode/electrolyte interface because they can work as reaction sites and/or recombination centers on the electrode surface⁸. Doping of Y and Yb enhanced light absorption efficiency (Figure 3b) better than W doped BiVO₄ sample. However, there are formation of recombination centers on the BiVO₄ photoanode surface (surface states) with Y& Yb doping and it remain even along with W co-doping. As given in above supporting Figure S3e, the SS has been reported to influence charge transfer at the semiconductor electrode/electrolyte interface because they can work as reaction sites and/or recombination centers on the photoanode surface. The irreversible peak (VO_2^+/VO^{2+} at ~ 1.45 V

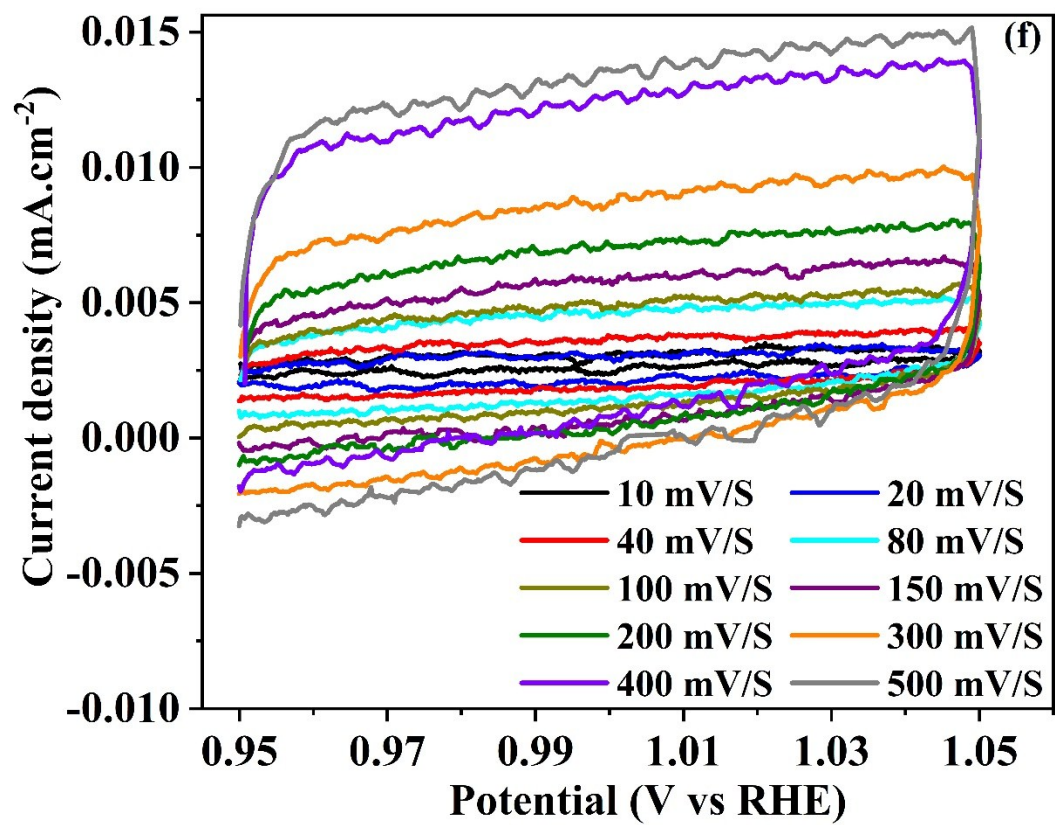
vs RHE, Figure S3e) intensity values follow the order: $(\text{Yb,W})\text{:BiVO}_4 > (\text{Y,W})\text{:BiVO}_4 > \text{W}\text{:BiVO}_4$, indicating formation of large number of recombination sites for the $(\text{Yb,W})\text{:BiVO}_4$ and $(\text{Y,W})\text{:BiVO}_4$ photoanodes. This is a direct evidence for the PCD with the following order: $(\text{Yb,W})\text{:BiVO}_4 < (\text{Y,W})\text{:BiVO}_4 < \text{W}\text{:BiVO}_4$. However, after forming heterojunction (WO_3) and surface catalyst Fe:NiO/Co-Pi , the additional enhancement in the PCD performance of $\text{WO}_3/(\text{Y,W})\text{:BiVO}_4/\text{Fe:NiO/Co-Pi}$ photoanode is due to effectively utilizing individual properties of Y and W in co-doped sample. The extended absorption behavior of Y (increased ϕ_{abs}) facilitates generation of increased charge pairs, WO_3 film help in transfer of highly mobile electrons from bulk to FTO interface and OER catalyst layer help in increasing charge transfer at the surface electrolyte interface⁵. On the other hand, PEC performance of $\text{WO}_3/\text{W}\text{:BiVO}_4$ photoanode did not increase very significantly because W helps in the charge separation and generation of free charge carriers in the bulk. But there are no additional charge carriers generated as it was observed in Y or Yb doping due to extended absorption.

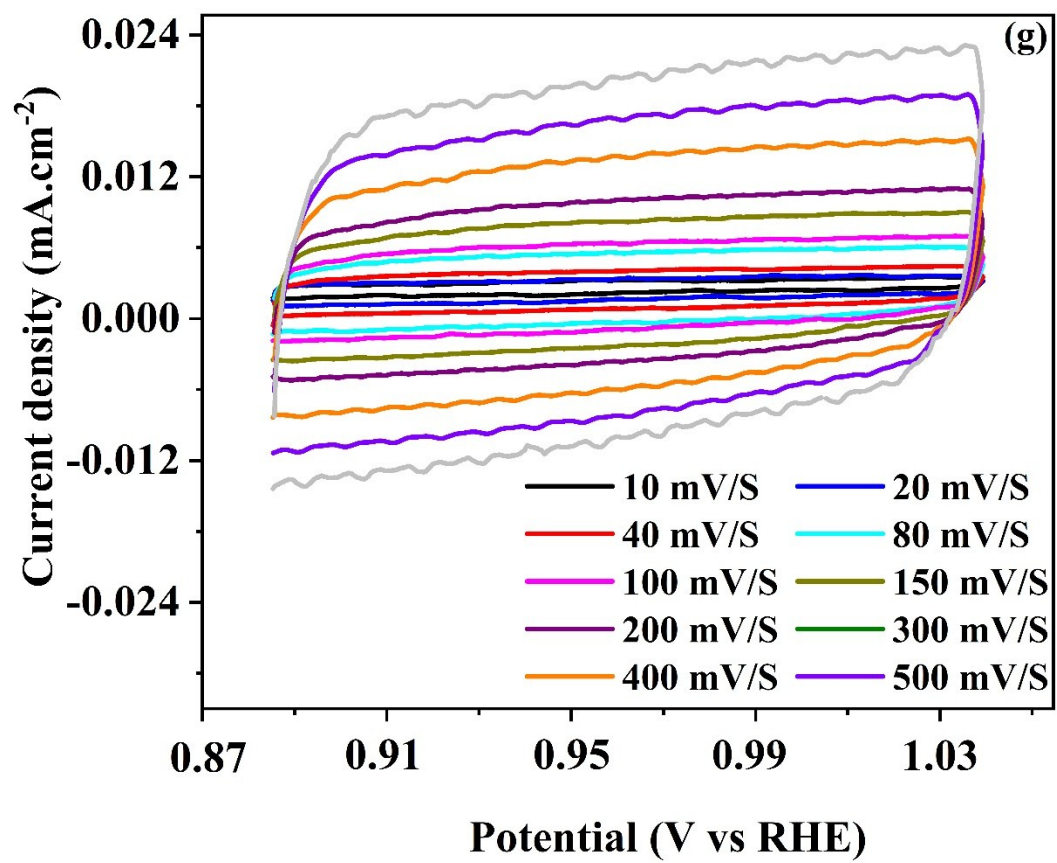












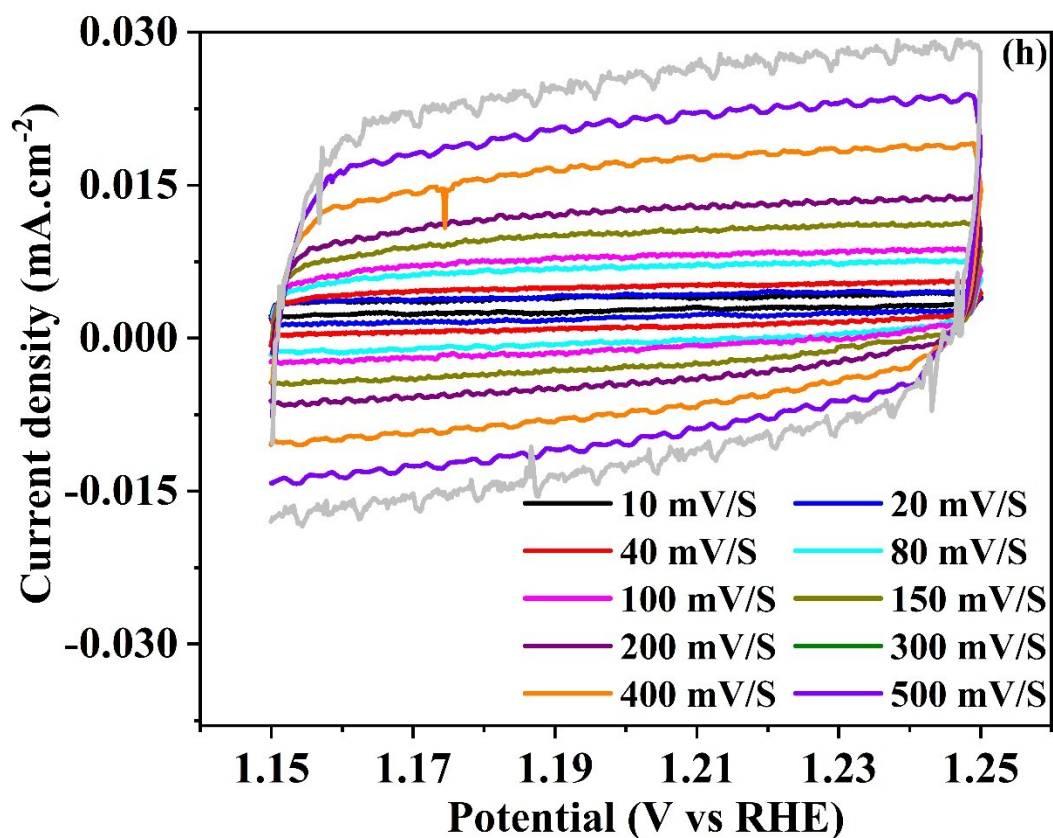
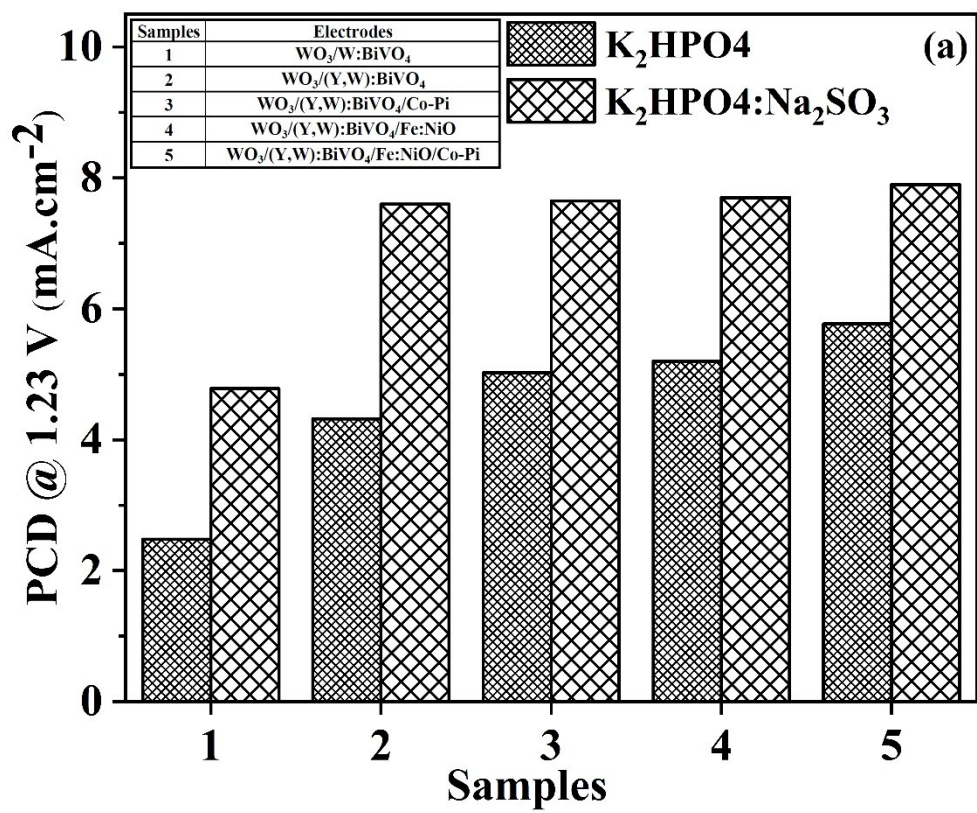
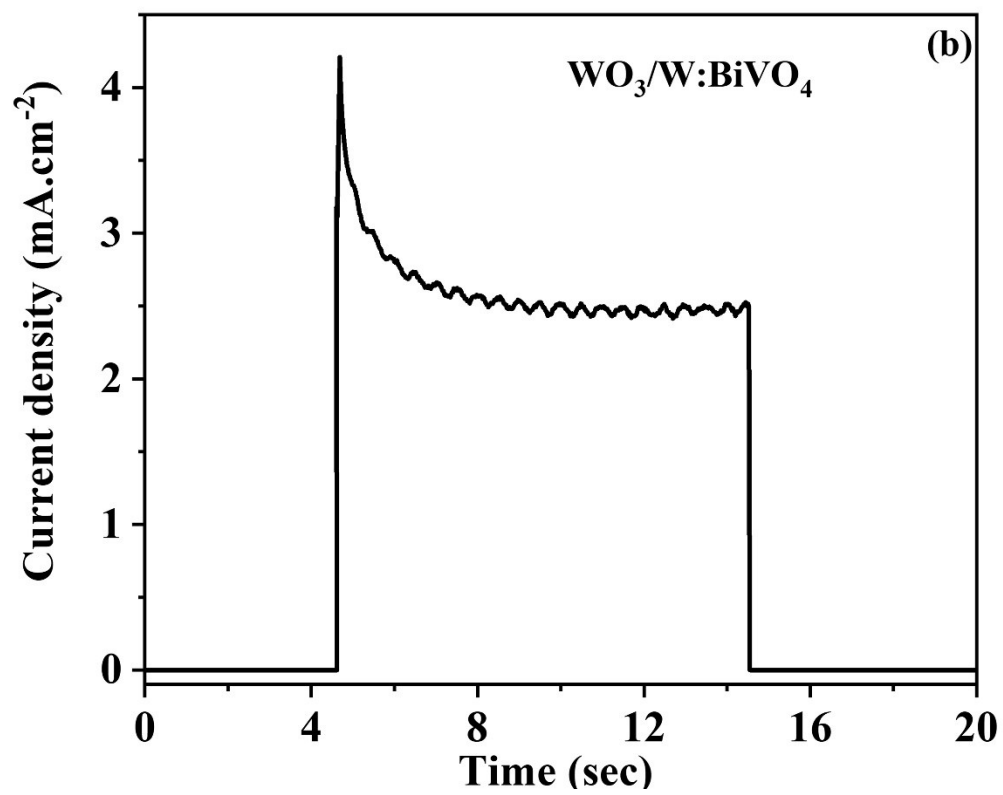
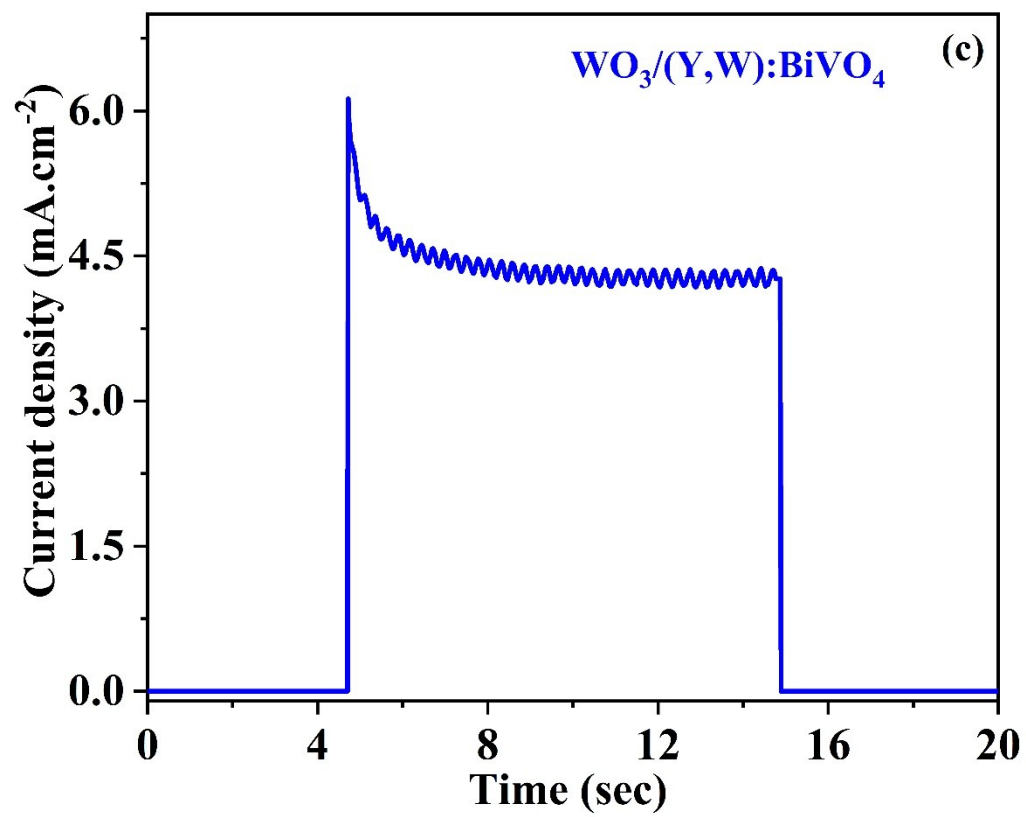
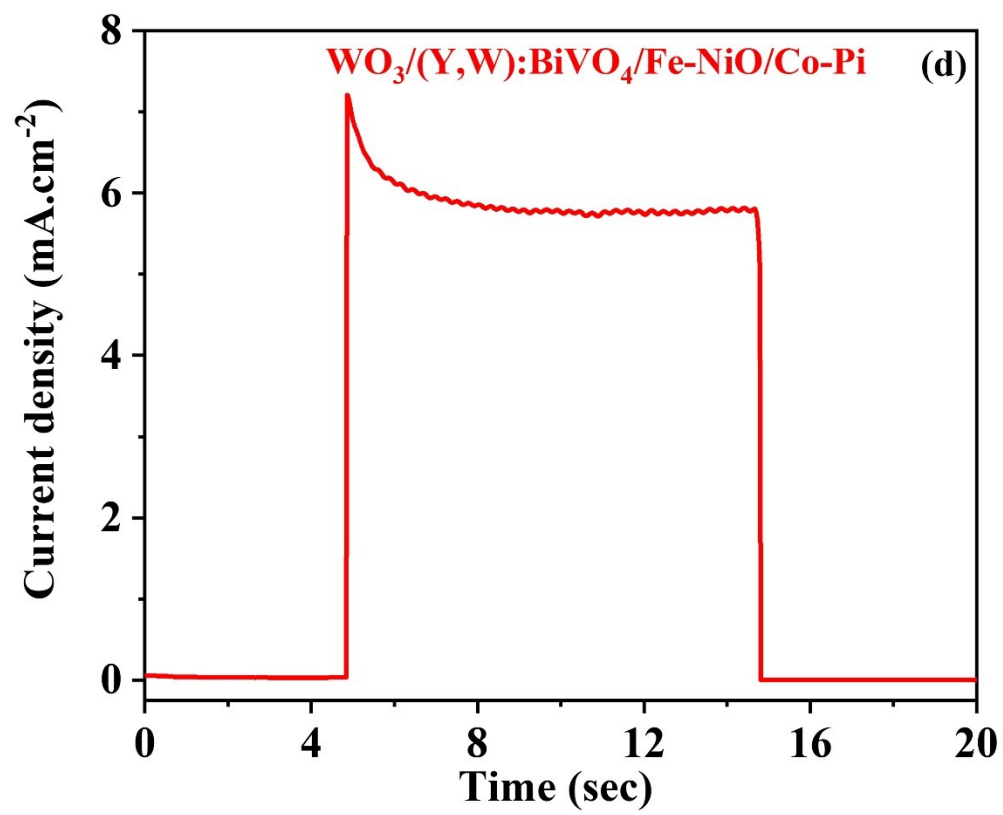


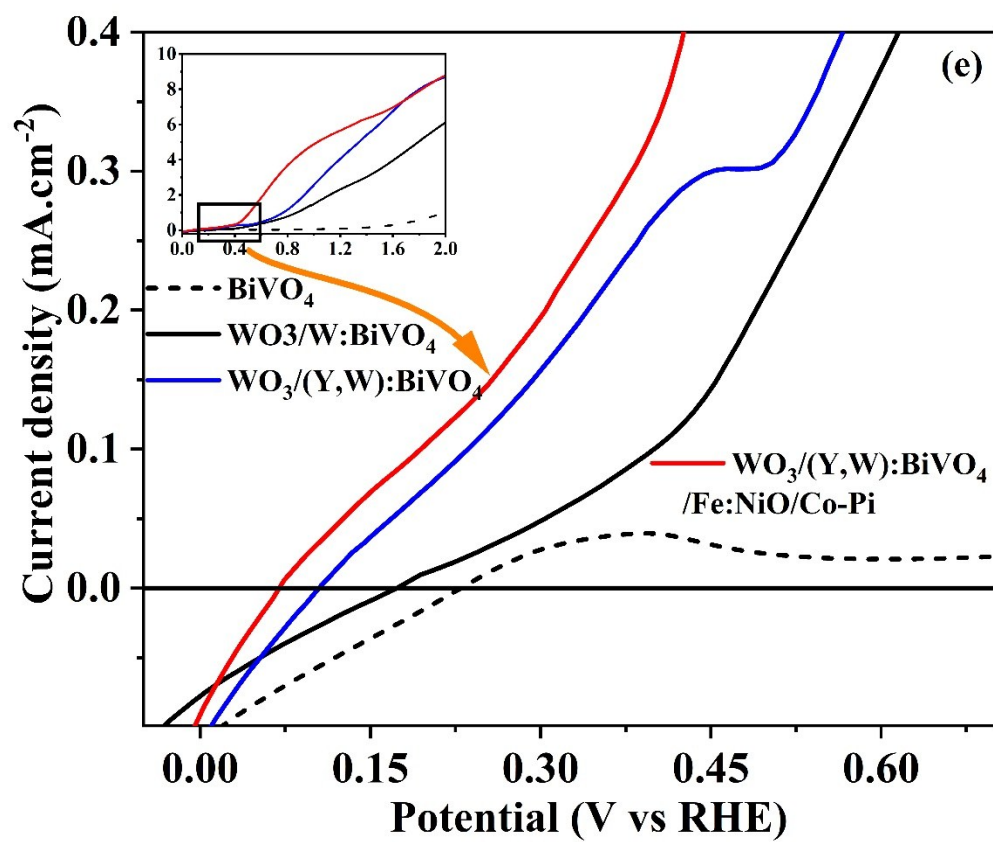
Figure S4. (a) Equivalent Randles circuit, (b) electrochemical surface area (ECSA) plot for pristine BiVO₄, Yb:BiVO₄, Y:BiVO₄, W:BiVO₄, (Yb,W): BiVO₄ and (Y,W):BiVO₄ photoanodes. Cyclic voltammetry curves in dark for (c) pristine BiVO₄, (d) Yb:BiVO₄, (e) Y:BiVO₄, (f) W:BiVO₄, (g) (Yb,W): BiVO₄ and (h) (Y,W):BiVO₄ photoanodes. The dark current measured at 1.03 V vs RHE.

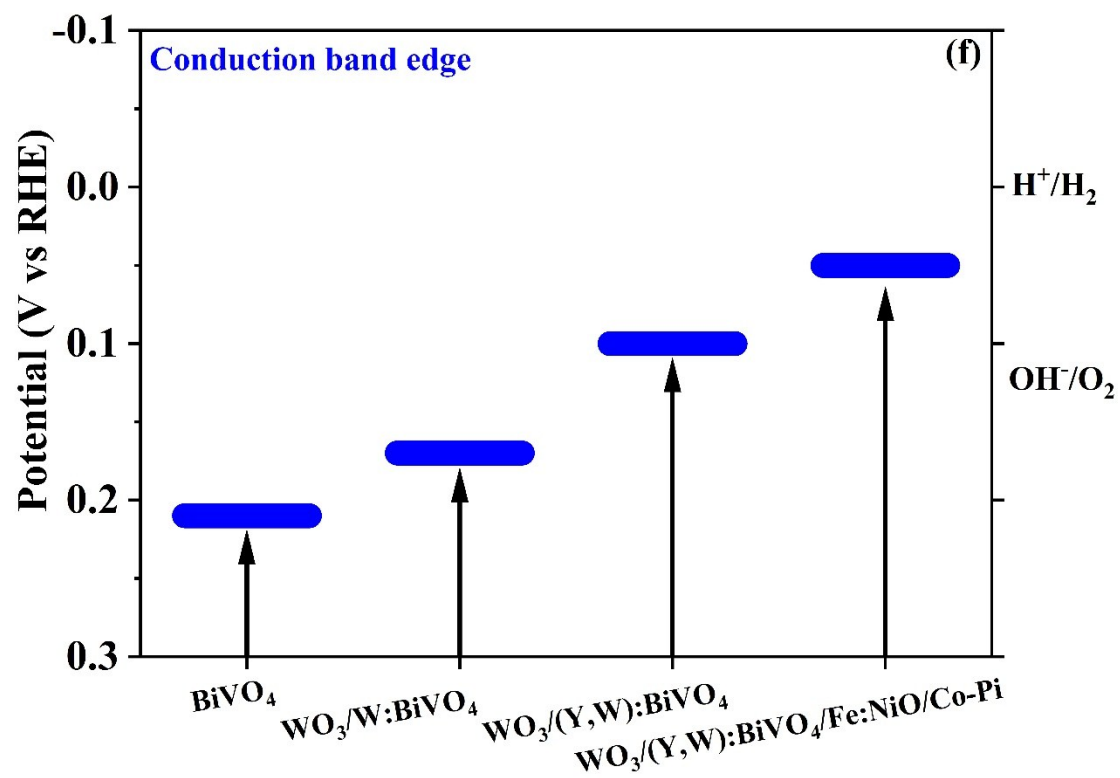


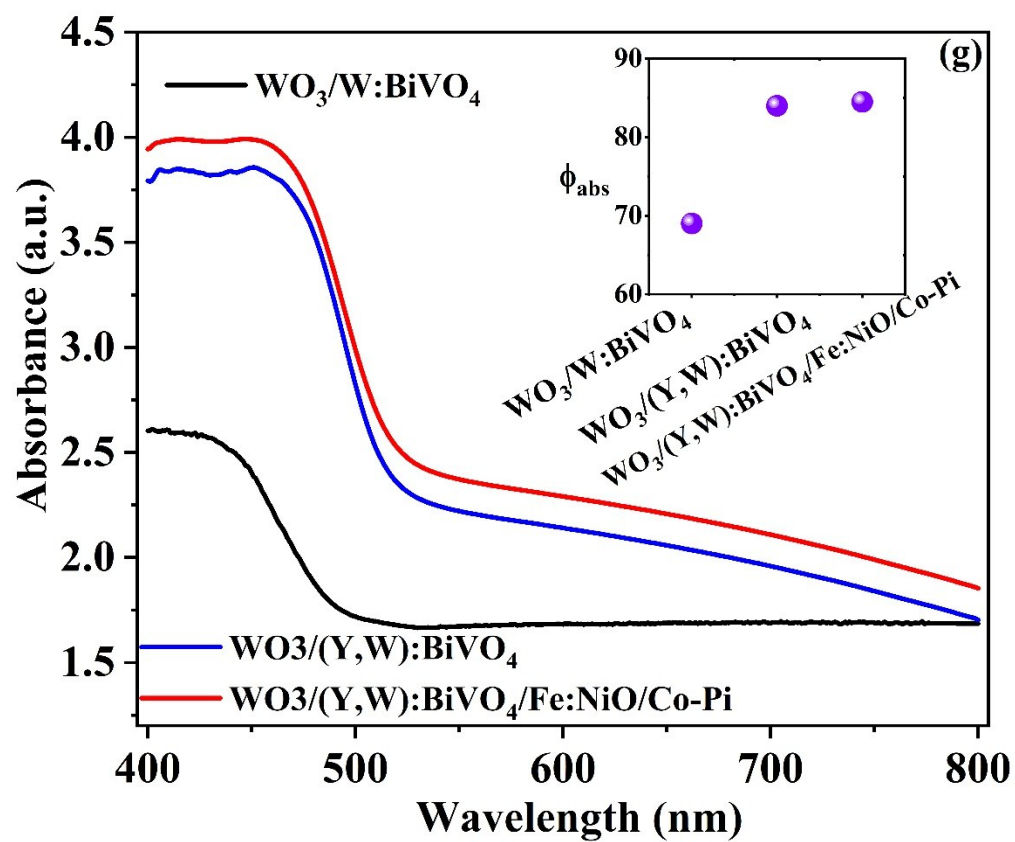


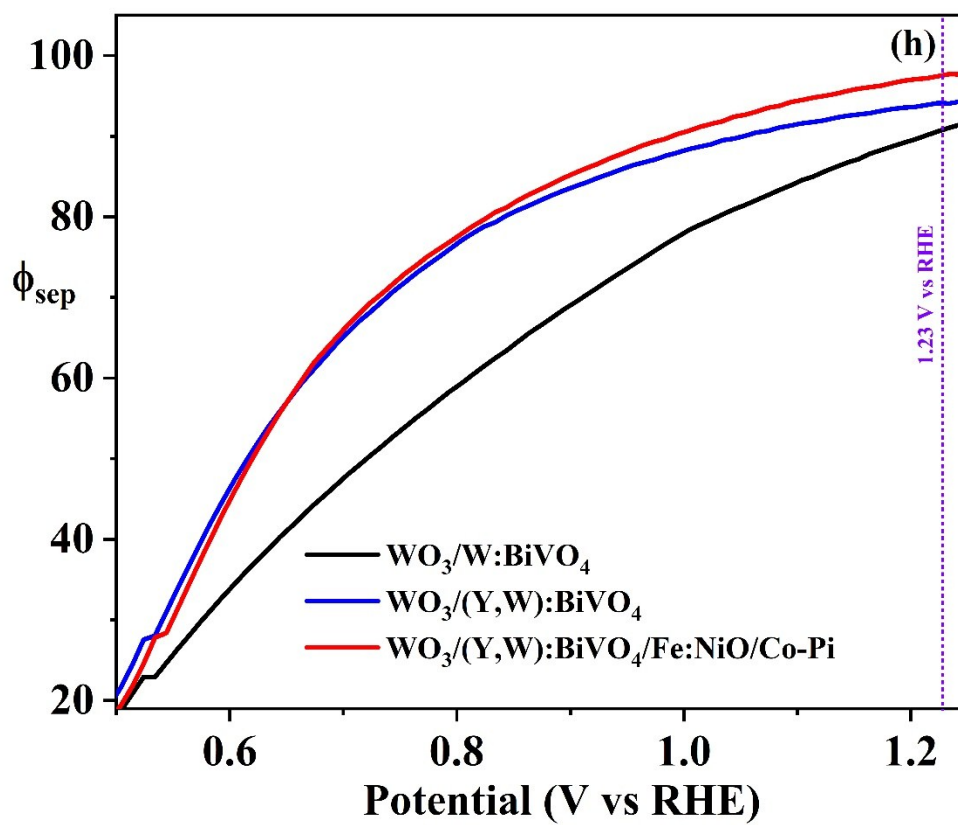












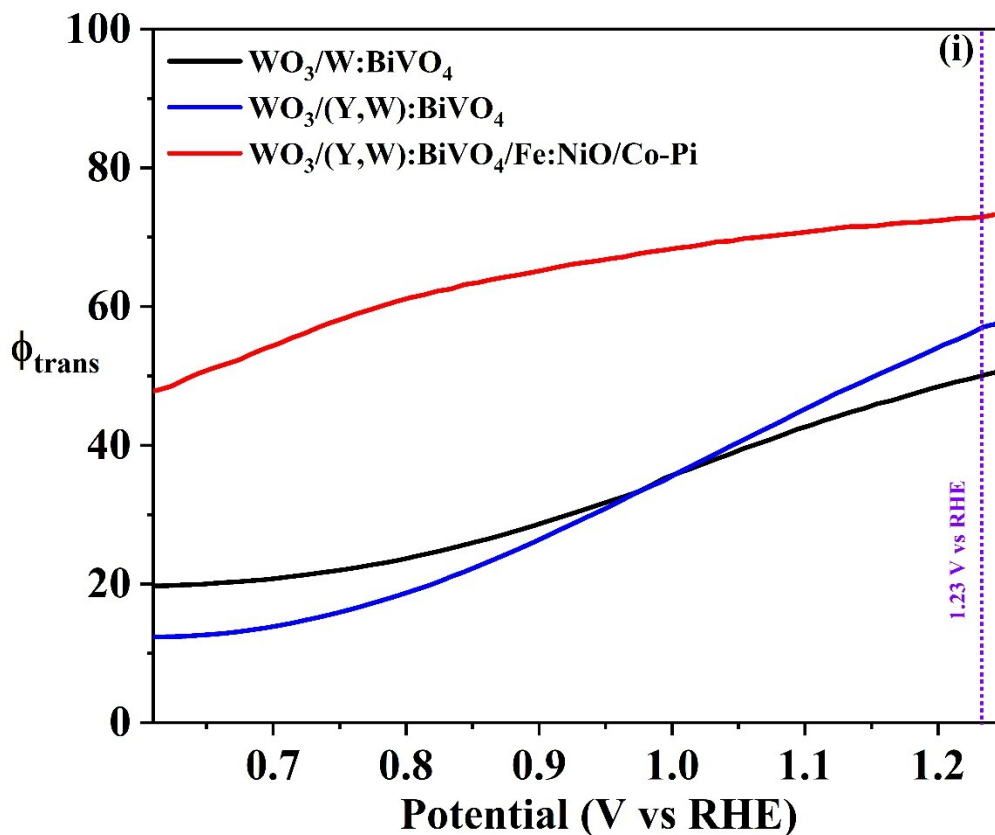
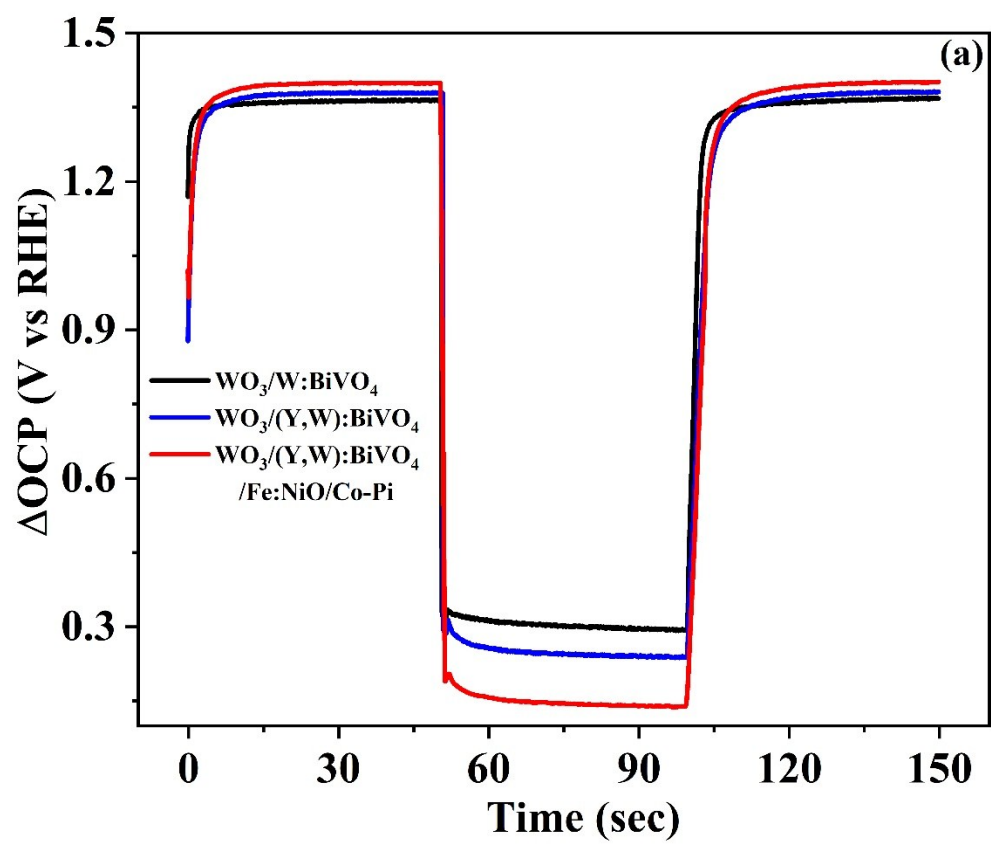


Figure S5. (a) PCD values after catalyst Fe:NiO and Co-Pi at 1.23 V vs RHE. (b-d) Transient current plots measured for 10 sec at 1.23 V vs RHE in 0.1 M K₂HPO₄ electrolyte at 1sun illumination, (e) current onset plot, (f) shift in conduction band edge for BiVO₄, WO₃/W:BiVO₄, WO₃/(Y,W):BiVO₄ and WO₃/(Y,W):BiVO₄/Fe:NiO/Co-Pi photoanode, (g) UV-vis absorption spectra, absorption efficiency (inset), (h) ϕ_{sep} plot, (i) ϕ_{trans} plot for WO₃/W:BiVO₄, WO₃/(Y,W):BiVO₄ and WO₃/(Y,W):BiVO₄/Fe:NiO/Co-Pi photoanodes.



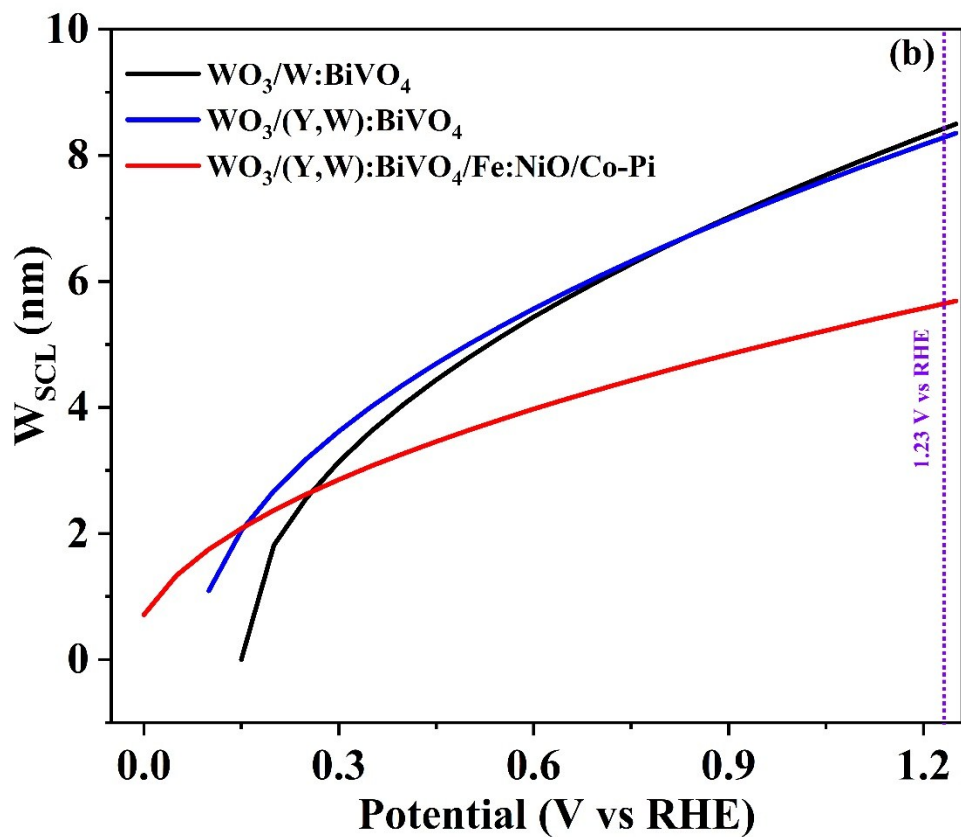


Figure S6 (a) Open circuit potential (ΔOCP), (b) space charge width (SCL) plot for $WO_3/W:BiVO_4$, $WO_3/(Y,W):BiVO_4$ and $WO_3/(Y,W):BiVO_4/Fe:NiO/Co-Pi$ photoanodes.

Table S1. Cell parameters evaluated from Rietveld refinement for pristine BiVO_4 , $\text{Yb}:\text{BiVO}_4$, $\text{Y}:\text{BiVO}_4$, $\text{W}:\text{BiVO}_4$, $(\text{Yb},\text{W}):\text{BiVO}_4$ and $(\text{Y},\text{W}):\text{BiVO}_4$ samples.

Photoanode	Lattice parameter, a (Å)	Lattice parameter, b (Å)	Lattice parameter, c (Å)	Angle (Degree)	Volume, (Å ³)
BiVO_4	5.1758	5.1079	11.6707	89.9270	308.5515
$\text{Yb}:\text{BiVO}_4$	5.1759	5.1002	11.6811	89.9985	308.3630
$\text{Y}:\text{BiVO}_4$	5.1808	5.1034	11.6579	89.9905	308.2370
$\text{W}:\text{BiVO}_4$	5.1759	5.1042	11.6743	89.9975	308.42133
$(\text{Yb},\text{W}):\text{BiVO}_4$	5.1768	5.09729	11.6841	89.9990	308.3204
$(\text{Y},\text{W}):\text{BiVO}_4$	5.1808	5.1034	11.6571	89.9989	308.2101

Table S2. Calculated parameters pristine BiVO_4 , $\text{Yb}:\text{BiVO}_4$, $\text{Y}:\text{BiVO}_4$, $\text{W}:\text{BiVO}_4$, $(\text{Yb},\text{W}):\text{BiVO}_4$ and $(\text{Y},\text{W}):\text{BiVO}_4$ photoanodes.

Photoanodes	$J_{\text{theoretical}}$ (mA.cm ⁻²)	ϕ_{abs} (%)	ϕ_{sep} (%)	ϕ_{trans} (%)	$\phi_{\text{abs}} \times \phi_{\text{sep}} \times \phi_{\text{trans}}$ (%)	Band gap (eV)
BiVO_4	7.5	62 ± 3	26 ± 1.4	8 ± 0.4	1.29 ± 0.07	2.51
$\text{Yb}:\text{BiVO}_4$	9.6	68 ± 3.2	34 ± 1.8	12 ± 0.5	2.77 ± 0.14	2.37
$\text{Y}:\text{BiVO}_4$	9.6	73 ± 4	38 ± 2	14 ± 0.8	3.88 ± 0.2	2.29
$\text{W}:\text{BiVO}_4$	7.5	63 ± 3.1	79.5 ± 4	55 ± 2.8	27.55 ± 1.38	2.51
$(\text{Yb},\text{W}):\text{BiVO}_4$	9.6	71 ± 3.5	67.5 ± 3.4	28 ± 1.5	13.42 ± 0.7	2.37
$(\text{Y},\text{W}):\text{BiVO}_4$	9.6	77 ± 3.9	73 ± 4	36 ± 1.8	20.24 ± 1	2.29

R_b (kΩ)	R_s (kW)	C_b (μF)	C_s (μF)	A_{ECSA} (cm ²)	N_D (cm ⁻³)	PCD (mA.cm ⁻²)
2.1 ± 0.1	4.33 ± 0.22	409 ± 20.4	36.5 ± 1.9	0.44 ± 0.024	2.8916E+19	0.095 ± 0.005
1.82 ± 0.094	3.81 ± 0.19	242 ± 12.5	83.2 ± 4.2	0.56 ± 0.03	3.0116E+19	0.26 ± 0.013
1.64 ± 0.083	3.62 ± 0.18	173 ± 8.7	190 ± 9.5	0.68 ± 0.035	3.7816E+19	0.37 ± 0.17
0.48 ± 0.025	0.85 ± 0.043	5.4 ± 0.45	410 ± 20.5	1.16 ± 0.06	1.07236E+20	2.2 ± 0.13
0.51 ± 0.056	1.19 ± 0.06	8.3 ± 0.52	334 ± 17	0.92 ± 0.1	9.62267E+19	1.29 ± 0.06
0.49 ± 0.024	0.96 ± 0.05	6.27 ± 0.48	387 ± 20	1.05 ± 0.055	1.04236E+20	1.94 ± 0.1

Table S3. Calculated parameters $WO_3/W:BiVO_4$, $WO_3/(Y,W):BiVO_4$ and

Photoanodes	$J_{\text{theoretical}}$ (mA.cm ⁻²)	ϕ_{abs} (%)	ϕ_{sep} (%)	ϕ_{trans} (%)	$\phi_{\text{abs}} \times$ $\phi_{\text{sep}} \times$ ϕ_{trans} (%)	Total charge recobine (%)	N_D (cm ⁻³)
$BiVO_4$						90 ± 5	$2.8916E+19$
$WO_3/W:BiVO_4$	7.5	71 ± 3.6	92 ± 4.8	50.5 ± 2.5	33 ± 2.5	42 ± 2	$1.14522E+20$
$WO_3/(Y,W):BiVO_4$	9.6	84 ± 4.5	94 ± 4.7	57 ± 3	45 ± 2.9	31 ± 2	$1.26141E+20$
$WO_3/(Y,W):BiVO_4/Fe:NiO/Co-Pi$	9.6	84 ± 4.5	98 ± 5	73 ± 4	60 ± 3.7	19 ± 1.2	$2.95041E+20$

$WO_3(Y,W):BiVO_4/Fe:NiO/Co-Pi$ photoanodes.

V_{onset} (V vs RHE)	V_{FB} (V vs RHE)	ΔOCP (V vs RHE)	W_{SCL} (nm)	Band Bending (mV vs RHE)	A_{ECSA} (cm ²)	IPCE (%)
0.23	0.21		16.24	0 ± 0		3.3 ± 0.17
0.18	0.15	0.3	8.43	35.34 ± 1.8	1.2 ± 0.025	45 ± 2.15
0.11	0.08	0.24	8.29	37.83 ± 1.9	1.35 ± 0.08	73 ± 3
0.07	0.03	0.15	5.67	60 ± 0.3	1.46 ± 0.1	97 ± 4.5

APCE (%)	$J_{\text{Integrated}}$ (mA.cm ⁻²)	PCD (mA.cm ⁻²)	PCD with hole scavengers (mA.cm ⁻²)
4 ± 0.18	0.15 ± 0.0075		
51 ± 2.5	2.6 ± 0.15	2.48 ± 0.12	4.78 ± 0.28
82 ± 2.6	4.38 ± 0.22	4.32 ± 0.22	7.6 ± 0.4
~ 98	5.81 ± 0.3	5.77 ± 0.3	7.8 ± 0.5

Supplementary reference:

- 1 J. Jia, L. C. Seitz, J. D. Benck, Y. Huo, Y. Chen, J. W. D. Ng, T. Bilir, J. S. Harris and T. F. Jaramillo, *Nat. Commun.*, 2016, **7**, 1–6.
- 2 U. Prasad, J. Prakash, B. Azeredo and A. Kannan, *Electrochim. Acta*, 2019, **299**, 262–272.
- 3 Y. Ma, S. R. Pendlebury, A. Reynal, F. Le Formal and J. R. Durrant, *Chem. Sci.*, 2014, **5**, 2964–2973.
- 4 W. He, R. Wang, C. Zhou, J. Yang, F. Li and X. Xiang, *Ind. Eng. Chem. Res.*, 2015, **54**, 10723–10730.
- 5 U. Prasad, J. Prakash, S. K. Gupta, J. Zuniga, Y. Mao, B. Azeredo and A. N. M. Kannan, *ACS Appl. Mater. Interfaces*, 2019, **11**, 19029–19039.
- 6 F. F. Abdi, L. Han, A. H. M. Smets, M. Zeman, B. Dam and R. Van De Krol, *Nat. Commun.*, 2013, **4**, 1–7.
- 7 Q. Shi, S. Murcia-López, P. Tang, C. Flox, J. R. Morante, Z. Bian, H. Wang and T. Andreu, *ACS Catal.*, 2018, **8**, 3331–3342.
- 8 S. Trasa, A. Petrii and K. Niki, *J. N. Agar (UK J. Koryta (Czechoslovakia Plieth (FRG*, 1992, **321**, 353–376.